

	6	7
System Frequency ( $f_{CK}$ )	166 MHz	143 MHz
Clock Cycle Time ( $t_{CK3}$ )	6 ns	7 ns
Clock Access Time ( $t_{AC3}$ ) $\overline{\text{CAS}}$ Latency = 3	5.4 ns	5.4 ns
Clock Access Time ( $t_{AC2}$ ) $\overline{\text{CAS}}$ Latency = 2	5.4 ns	5.4 ns

### Features

- 4 banks x 2Mbit x 16 organization
- High speed data transfer rates up to 166 MHz
- Full Synchronous Dynamic RAM, with all signals referenced to clock rising edge
- Single Pulsed RAS Interface
- Data Mask for Read/Write Control
- Four Banks controlled by BA0 & BA1
- Programmable CAS Latency: 2, 3
- Programmable Wrap Sequence: Sequential or Interleave
- Programmable Burst Length:  
1, 2, 4, 8, and full page for Sequential Type  
1, 2, 4, 8 for Interleave Type
- Multiple Burst Read with Single Write Operation
- Automatic and Controlled Precharge Command
- Random Column Address every CLK (1-N Rule)
- Power Down Mode
- Auto Refresh and Self Refresh
- Refresh Interval: 4096 cycles/64 ms
- Available in 54-Pin TSOP II
- LVTTTL Interface
- Single +3.3 V  $\pm 0.3$  V Power Supply

### Description

The D54C3128164VF is a four bank Synchronous DRAM organized as 4 banks x 2Mbit x 16. The D54C3128164VF achieves high speed data transfer rates up to 166 MHz by employing a chip architecture that prefetches multiple bits and then synchronizes the output data to a system clock.

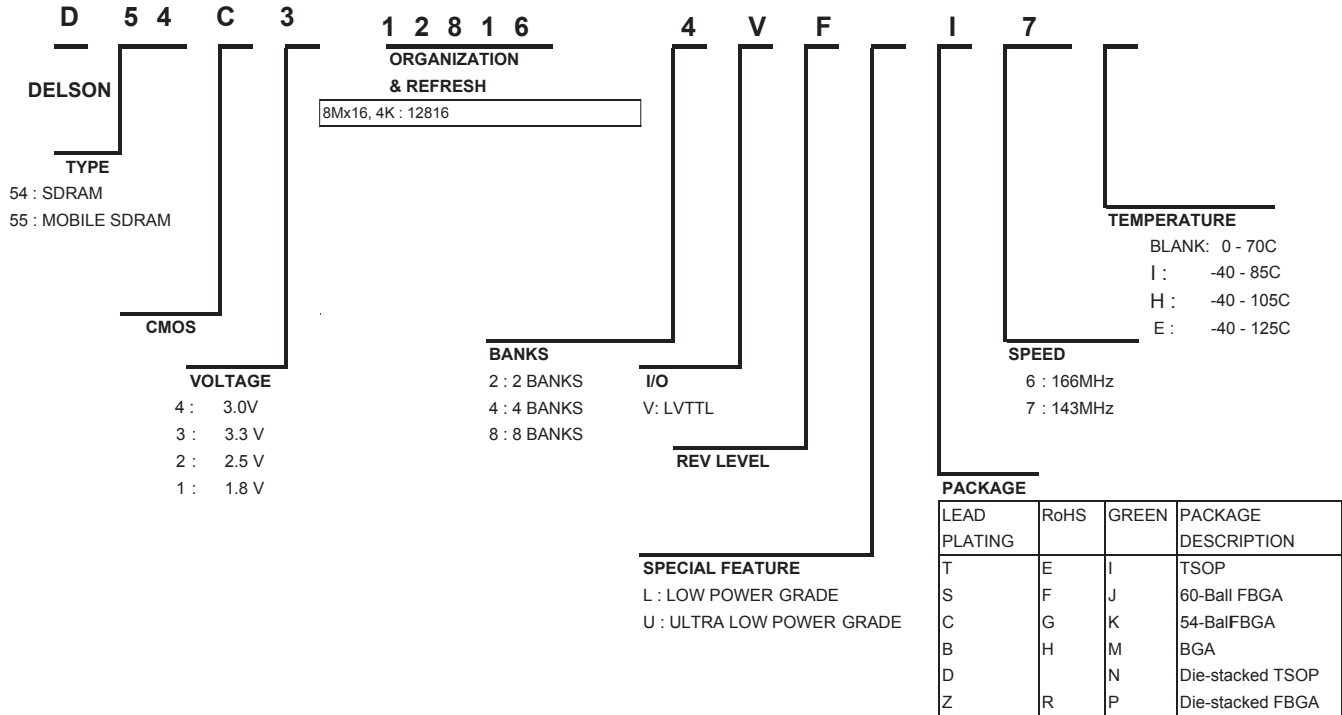
All of the control, address, data input and output circuits are synchronized with the positive edge of an externally supplied clock.

Operating the four memory banks in an interleaved fashion allows random access operation to occur at higher rate than is possible with standard DRAMs. A sequential and gapless data rate of up to 166 MHz is possible depending on burst length, CAS latency and speed grade of the device.

### Device Usage Chart

Operating Temperature Range	Package Outline	Access Time (ns)		Power	Temperature Mark
	I	6	7	Std.	
0°C to 70°C	•	•	•	•	Blank
-40°C to 85°C	•	•	•	•	I

**Part Number Information**



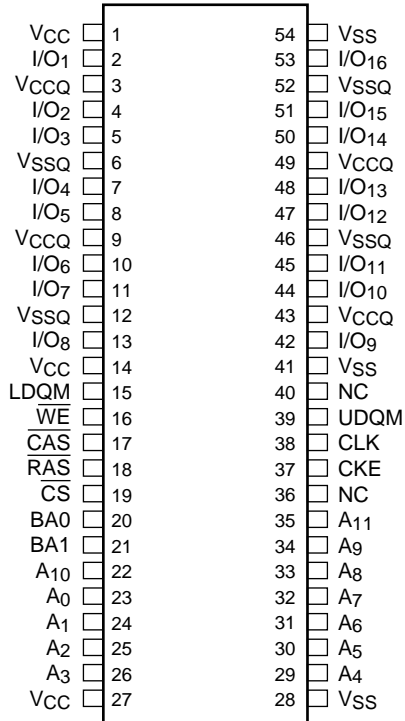
\* RoHS: Restriction of Hazardous Substances  
\* Green: RoHS-compliant and Halogen-free

**128Mb SDRAM Pin Assignment**  
(54-Pin TSOP-II)

Description	Pkg.	Pin Count
TSOP-II	I	54

**x16 Configuration**

**Top View**



**Pin Names**

CLK	Clock Input
CKE	Clock Enable
$\overline{CS}$	Chip Select
$\overline{RAS}$	Row Address Strobe
$\overline{CAS}$	Column Address Strobe
$\overline{WE}$	Write Enable
A <sub>0</sub> -A <sub>11</sub>	Address Inputs
BA0, BA1	Bank Select
I/O <sub>1</sub> -I/O <sub>16</sub>	Data Input/Output
LDQM, UDQM	Data Mask
V <sub>CC</sub>	Power (+3.3V)
V <sub>SS</sub>	Ground
V <sub>CCQ</sub>	Power for I/O's (+3.3V)
V <sub>SSQ</sub>	Ground for I/O's
NC	Not connected

**Capacitance\***

VCC=VCCQ=3.3V, TA=25°C, f=1MHz, pin under test biased at 1.4V.

Symbol	Parameter	Max.	Unit
C <sub>I1</sub>	Input Capacitance (A0 to A11)	3.5	pF
C <sub>I2</sub>	Input Capacitance RAS, CAS, WE, CS, CLK, CKE, DQM	3.5	pF
C <sub>IO</sub>	Output Capacitance (I/O)	5.5	pF
C <sub>CLK</sub>	Input Capacitance (CLK)	3.5	pF

\*Note:Capacitance is sampled and not 100% tested.

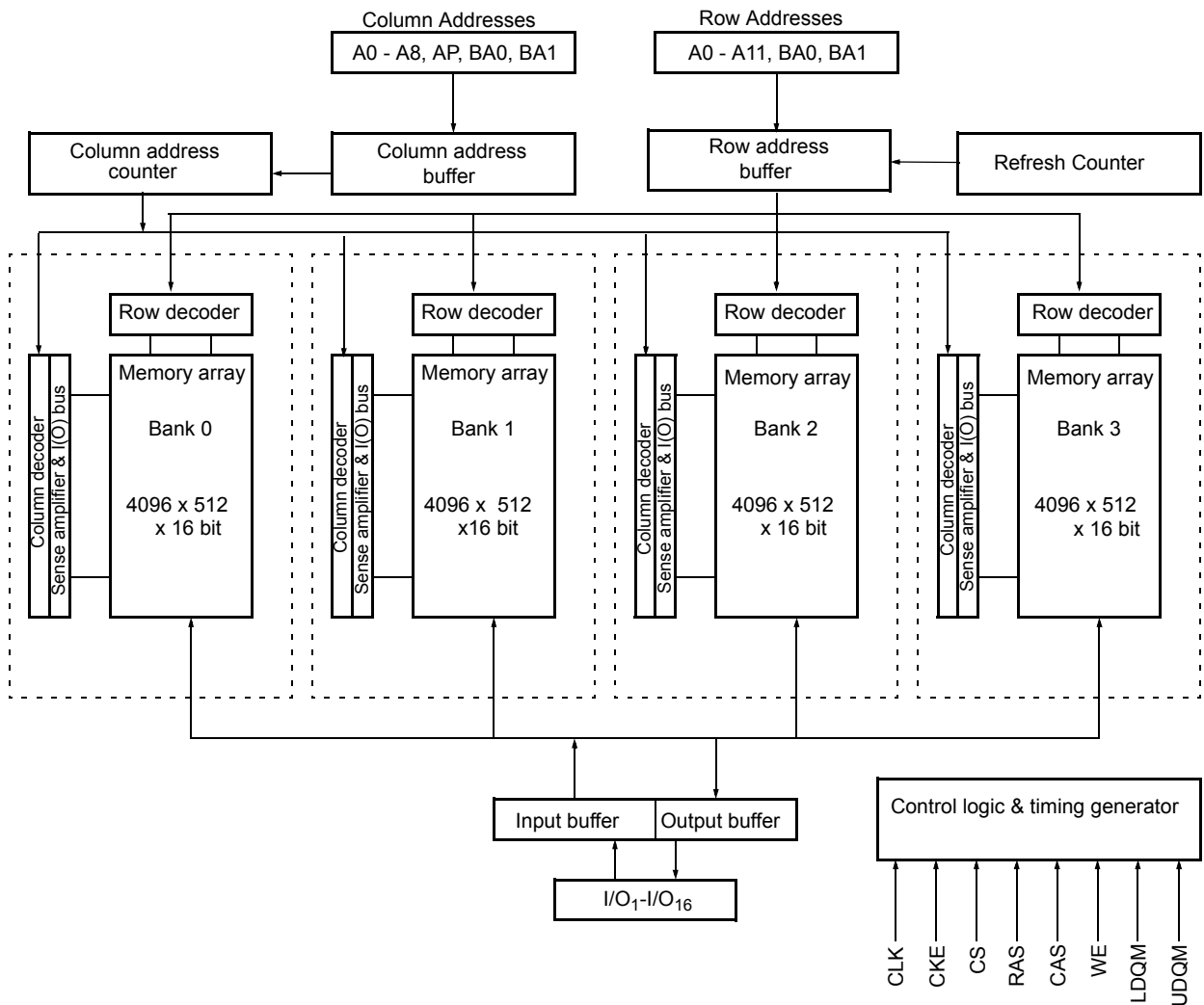
**Absolute Maximum Ratings\***

Operating temperature range ..... 0 to 70°C for normal  
 ..... -40 to 85 °C for industrial  
 Storage temperature range ..... -55 to 150 °C  
 Input/output voltage ..... -0.3 to (V<sub>CC</sub>+0.3) V  
 Power supply voltage ..... -1.0 to 4.6 V  
 Power dissipation ..... 1 W  
 Data out current (short circuit)..... 50 mA

\*Note: Stresses above those listed under “Absolute Maximum Ratings” may cause permanent damage of the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**Block Diagram**

**x16 Configuration**



**Signal Pin Description**

Pin	Type	Signal	Polarity	Function
CLK	Input	Pulse	Positive Edge	The system clock input. All of the SDRAM inputs are sampled on the rising edge of the clock.
CKE	Input	Level	Active High	Activates the CLK signal when high and deactivates the CLK signal when low, thereby initiates either the Power Down mode or the Self Refresh mode.
$\overline{CS}$	Input	Pulse	Active Low	$\overline{CS}$ enables the command decoder when low and disables the command decoder when high. When the command decoder is disabled, new commands are ignored but previous operations continue.
$\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$	Input	Pulse	Active Low	When sampled at the positive rising edge of the clock, $\overline{CAS}$ , $\overline{RAS}$ , and $\overline{WE}$ define the command to be executed by the SDRAM.
A0 - A11	Input	Level	—	<p>During a Bank Activate command cycle, A0-A11 defines the row address (RA0-RA11) when sampled at the rising clock edge.</p> <p>During a Read or Write command cycle, A0-An defines the column address (CA0-CAn) when sampled at the rising clock edge. CAn depends from the SDRAM organization:</p> <ul style="list-style-type: none"> <li>• 8M x 16 SDRAM CA0–CA8.</li> </ul> <p>In addition to the column address, A10(=AP) is used to invoke autoprecharge operation at the end of the burst read or write cycle. If A10 is high, autoprecharge is selected and BA0, BA1 defines the bank to be precharged. If A10 is low, autoprecharge is disabled.</p> <p>During a Precharge command cycle, A10(=AP) is used in conjunction with BA0 and BA1 to control which bank(s) to precharge. If A10 is high, all four banks will BA0 and BA1 are used to define which bank to precharge.</p>
BA0, BA1	Input	Level	—	Selects which bank is to be active.
DQx	Input Output	Level	—	Data Input/Output pins operate in the same manner as on conventional DRAMs.
LDQM UDQM	Input	Pulse	Active High	The Data Input/Output mask places the DQ buffers in a high impedance state when sampled high. In Read mode, DQM has a latency of two clock cycles and controls the output buffers like an output enable. In Write mode, DQM has a latency of zero and operates as a word mask by allowing input data to be written if it is low but blocks the write operation if DQM is high.
VCC, VSS	Supply			Power and ground for the input buffers and the core logic.
VCCQ VSSQ	Supply	—	—	Isolated power supply and ground for the output buffers to provide improved noise immunity.

**Operation Definition**

All of SDRAM operations are defined by states of control signals  $\overline{CS}$ ,  $\overline{RAS}$ ,  $\overline{CAS}$ ,  $\overline{WE}$ , and DQM at the positive edge of the clock. The following list shows the thruth table for the operation commands.

Operation	Device State	CKE n-1	CKE n	$\overline{CS}$	$\overline{RAS}$	$\overline{CAS}$	$\overline{WE}$	DQM	A0-9, A11	A10	BA0 BA1
Row Activate	Idle <sup>3</sup>	H	X	L	L	H	H	X	V	V	V
Read	Active <sup>3</sup>	H	X	L	H	L	H	X	V	L	V
Read w/Autoprecharge	Active <sup>3</sup>	H	X	L	H	L	H	X	V	H	V
Write	Active <sup>3</sup>	H	X	L	H	L	L	X	V	L	V
Write with Autoprecharge	Active <sup>3</sup>	H	X	L	H	L	L	X	V	H	V
Row Precharge	Any	H	X	L	L	H	L	X	X	L	V
Precharge All	Any	H	X	L	L	H	L	X	X	H	X
Mode Register Set	Idle	H	X	L	L	L	L	X	V	V	V
No Operation	Any	H	X	L	H	H	H	X	X	X	X
Device Deselect	Any	H	X	H	X	X	X	X	X	X	X
Auto Refresh	Idle	H	H	L	L	L	H	X	X	X	X
Self Refresh Entry	Idle	H	L	L	L	L	H	X	X	X	X
Self Refresh Exit	Idle (Self Refr.)	L	H	H	X	X	X	X	X	X	X
				L	H	H	X				
Power Down Entry	Idle Active <sup>4</sup>	H	L	H	X	X	X	X	X	X	X
				L	H	H	X				
Power Down Exit	Any (Power Down)	L	H	H	X	X	X	X	X	X	X
				L	H	H	L				
Data Write/Output Enable	Active	H	X	X	X	X	X	L	X	X	X
Data Write/Output Disable	Active	H	X	X	X	X	X	H	X	X	X

**Notes:**

1. V = Valid , x = Don't Care, L = Low Level, H = High Level
2. CKEn signal is input level when commands are provided, CKEn-1 signal is input level one clock before the commands are provided.
3. These are state of bank designated by BS0, BS1 signals.
4. Power Down Mode can not entry in the burst cycle.

### **Power On and Initialization**

The default power on state of the mode register is supplier specific and may be undefined. The following power on and initialization sequence guarantees the device is preconditioned to each users specific needs. Like a conventional DRAM, the Synchronous DRAM must be powered up and initialized in a predefined manner. During power on, all VCC and VCCQ pins must be built up simultaneously to the specified voltage when the input signals are held in the "NOP" state. The power on voltage must not exceed VCC+0.3V on any of the input pins or VCC supplies. The CLK signal must be started at the same time. After power on, an initial pause of 200 ms is required followed by a precharge of both banks using the precharge command. To prevent data contention on the DQ bus during power on, it is required that the DQM and CKE pins be held high during the initial pause period. Once all banks have been precharged, the Mode Register Set Command must be issued to initialize the Mode Register. A minimum of two Auto Refresh cycles (CBR) are also required. These may be done before or after programming the Mode Register. Failure to follow these steps may lead to unpredictable start-up modes.

### **Programming the Mode Register**

The Mode register designates the operation mode at the read or write cycle. This register is divided into 4 fields. A Burst Length Field to set the length of the burst, an Addressing Selection bit to program the column access sequence in a burst cycle (interleaved or sequential), a CAS Latency Field to set the access time at clock cycle and a Operation mode field to differentiate between normal operation (Burst read and burst Write) and a special Burst Read and Single Write mode. The mode set operation must be done before any activate command after the initial power up. Any content of the mode register can be altered by re-executing the

mode set command. All banks must be in pre-charged state and CKE must be high at least one clock before the mode set operation. After the mode register is set, a Standby or NOP command is required. Low signals of RAS, CAS, and WE at the positive edge of the clock activate the mode set operation. Address input data at this timing defines parameters to be set as shown in the previous table.

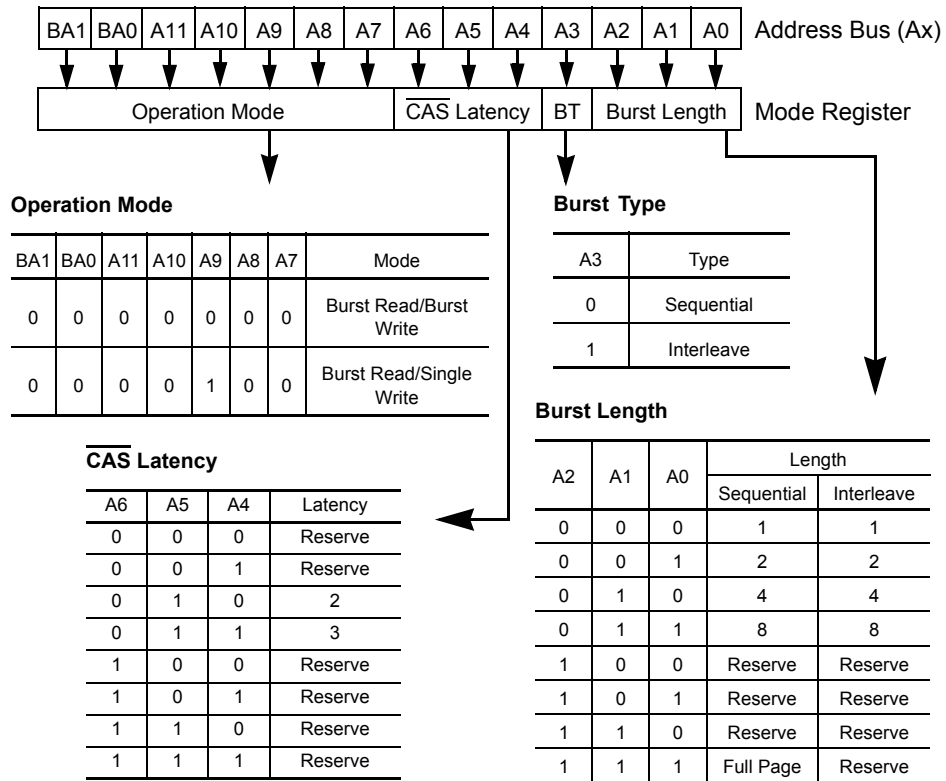
### **Read and Write Operation**

When  $\overline{\text{RAS}}$  is low and both  $\overline{\text{CAS}}$  and  $\overline{\text{WE}}$  are high at the positive edge of the clock, a RAS cycle starts. According to address data, a word line of the selected bank is activated and all of sense amplifiers associated to the wordline are set. A  $\overline{\text{CAS}}$  cycle is triggered by setting  $\overline{\text{RAS}}$  high and  $\overline{\text{CAS}}$  low at a clock timing after a necessary delay,  $t_{\text{RCD}}$ , from the  $\overline{\text{RAS}}$  timing.  $\overline{\text{WE}}$  is used to define either a read ( $\overline{\text{WE}} = \text{H}$ ) or a write ( $\overline{\text{WE}} = \text{L}$ ) at this stage.

SDRAM provides a wide variety of fast access modes. In a single CAS cycle, serial data read or write operations are allowed at up to a 166 MHz data rate. The numbers of serial data bits are the burst length programmed at the mode set operation, i.e., one of 1, 2, 4, 8 and full page. Column addresses are segmented by the burst length and serial data accesses are done within this boundary. The first column address to be accessed is supplied at the CAS timing and the subsequent addresses are generated automatically by the programmed burst length and its sequence. For example, in a burst length of 8 with interleave sequence, if the first address is '2', then the rest of the burst sequence is 3, 0, 1, 6, 7, 4, and 5.

Full page burst operation is only possible using sequential burst type. Full Page burst operation does not terminate once the burst length has been reached. (At the end of the page, it will wrap to the start address and continue.) In other words, unlike burst length of 2, 4, and 8, full page burst continues until it is terminated using another command.

**Address Input for Mode Set (Mode Register Operation)**



Similar to the page mode of conventional DRAM's, burst read or write accesses on any column address are possible once the RAS cycle latches the sense amplifiers. The maximum  $t_{RAS}$  or the refresh interval time limits the number of random column accesses. A new burst access can be done even before the previous burst ends. The interrupt operation at every clock cycles is supported. When the previous burst is interrupted, the remaining addresses are overridden by the new address with the full burst length. An interrupt which accompanies with an operation change from a read to a write is possible by exploiting DQM to avoid bus contention.

When two or more banks are activated sequentially, interleaved bank read or write operations are possible. With the programmed burst length, alternate access and precharge operations on two or more banks can realize fast serial data access modes among many different pages. Once two or more banks are activated, column to column interleave operation can be done between different pages.



**Burst Length and Sequence:**

Burst Length	Starting Address (A2 A1 A0)	Sequential Burst Addressing (decimal)	Interleave Burst Addressing (decimal)
2	xx0	0, 1	0, 1
	xx1	1, 0	1, 0
4	x00	0, 1, 2, 3	0, 1, 2, 3
	x01	1, 2, 3, 0	1, 0, 3, 2
	x10	2, 3, 0, 1	2, 3, 0, 1
	x11	3, 0, 1, 2	3, 2, 1, 0
8	000	0 1 2 3 4 5 6 7	0 1 2 3 4 5 6 7
	001	1 2 3 4 5 6 7 0	1 0 3 2 5 4 7 6
	010	2 3 4 5 6 7 0 1	2 3 0 1 6 7 4 5
	011	3 4 5 6 7 0 1 2	3 2 1 0 7 6 5 4
	100	4 5 6 7 0 1 2 3	4 5 6 7 0 1 2 3
	101	5 6 7 0 1 2 3 4	5 4 7 6 1 0 3 2
	110	6 7 0 1 2 3 4 5	6 7 4 5 2 3 0 1
	111	7 0 1 2 3 4 5 6	7 6 5 4 3 2 1 0
Full Page	nnn	Cn, Cn+1, Cn+2....	not supported

**Refresh Mode**

SDRAM has two refresh modes, Auto Refresh and Self Refresh. Auto Refresh is similar to the  $\overline{\text{CAS}}$ -before-RAS refresh of conventional DRAMs. All of banks must be precharged before applying any refresh mode. An on-chip address counter increments the word and the bank addresses and no bank information is required for both refresh modes.

The chip enters the Auto Refresh mode, when  $\overline{\text{RAS}}$  and  $\overline{\text{CAS}}$  are held low and CKE and  $\overline{\text{WE}}$  are held high at a clock timing. The mode restores word line after the refresh and no external precharge command is necessary. A minimum tRC time is required between two automatic refreshes in a burst refresh mode. The same rule applies to any access command after the automatic refresh operation.

The chip has an on-chip timer and the Self Refresh mode is available. It enters the mode when  $\overline{\text{RAS}}$ ,  $\overline{\text{CAS}}$ , and CKE are low and  $\overline{\text{WE}}$  is high at a clock timing. All of external control signals including the clock are disabled. Returning CKE to high enables the clock and initiates the refresh exit operation. After the exit command, at least one tRC delay is required prior to any access command.

**DQM Function**

DQM has two functions for data I/O read and write operations. During reads, when it turns to “high” at a clock timing, data outputs are disabled and become high impedance after two clock delay (DQM Data Disable Latency tDQZ ). It also provides a data mask function for writes. When DQM is activated, the write operation at the next clock is prohibited (DQM Write Mask Latency tDQW = zero clocks).

**Power Down**

In order to reduce standby power consumption, a power down mode is available. All banks must be precharged and the necessary Precharge delay (trp) must occur before the SDRAM can enter the Power Down mode. Once the Power Down mode is initiated by holding CKE low, all of the receiver circuits except CLK and CKE are gated off. The Power Down mode does not perform any refresh operations, therefore the device can’t remain in Power Down mode longer than the Refresh period (tref) of the device. Exit from this mode is performed by taking CKE “high”. One clock delay is required for mode entry and exit.







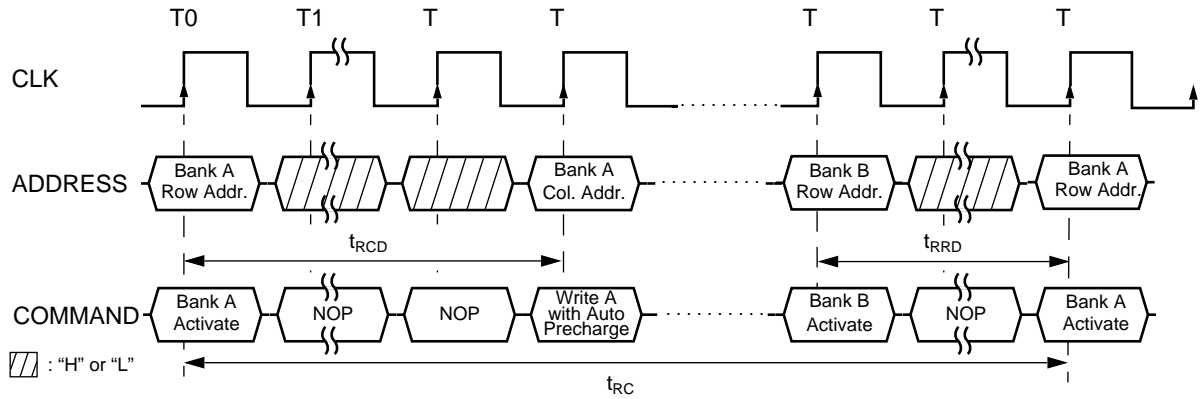






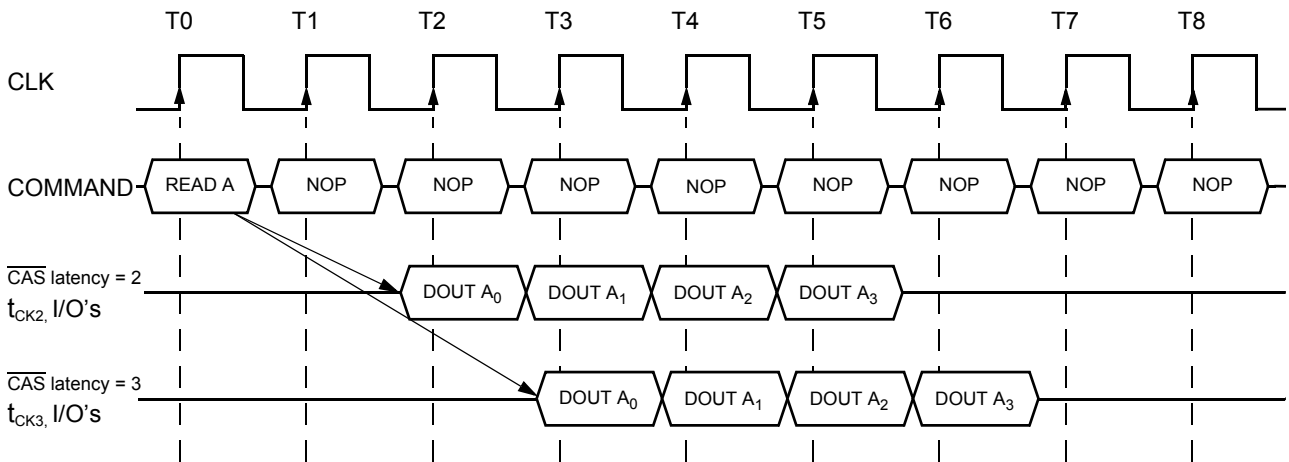
**1. Bank Activate Command Cycle**

( $\overline{\text{CAS}}$  latency = 3)



**2. Burst Read Operation**

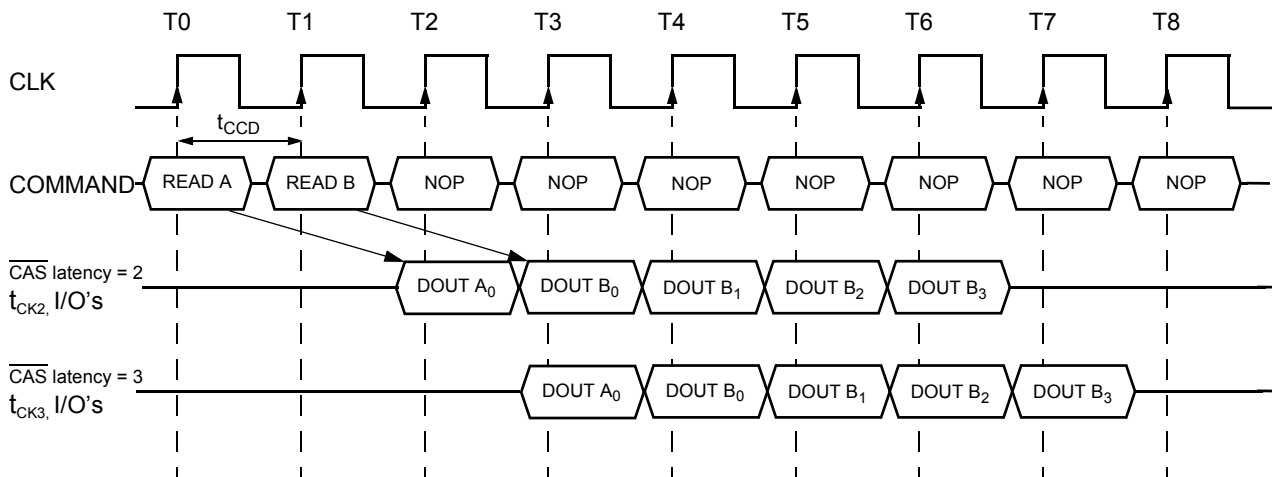
(Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2, 3)





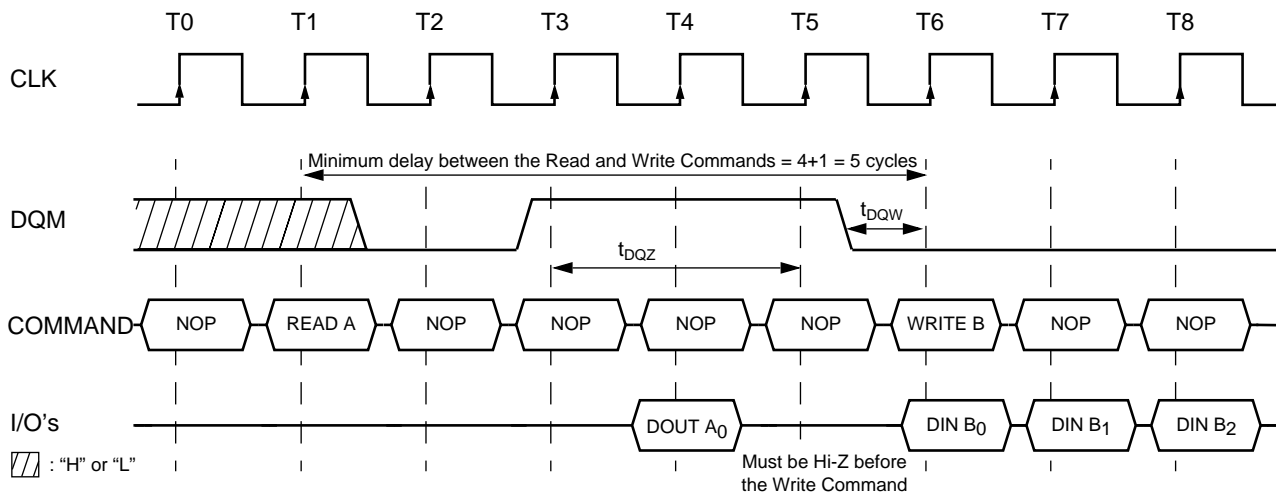
**3. Read Interrupted by a Read**

(Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2, 3)



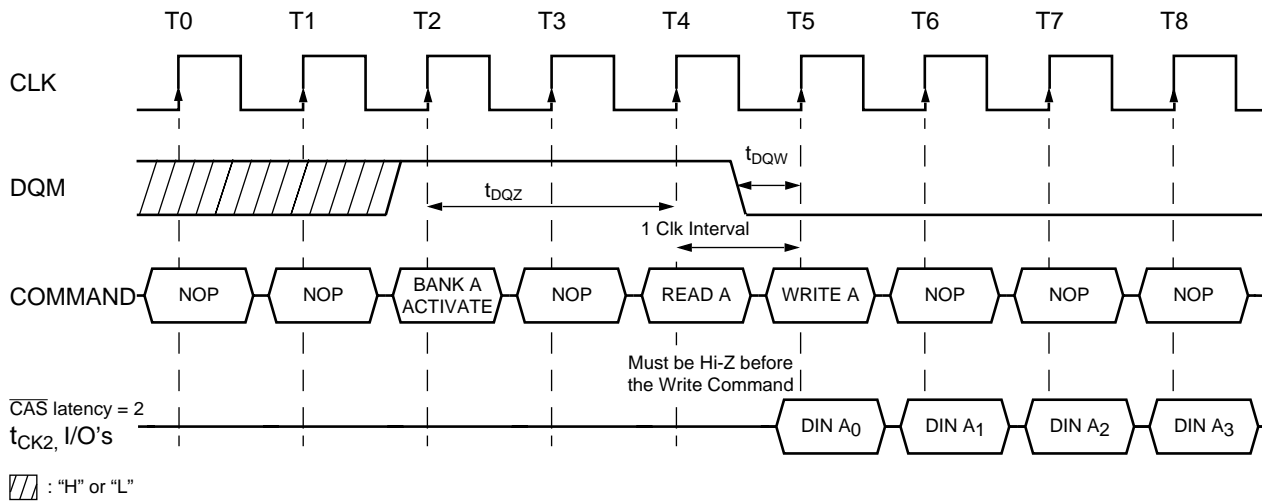
**4.1 Read to Write Interval**

(Burst Length = 4,  $\overline{\text{CAS}}$  latency = 3)



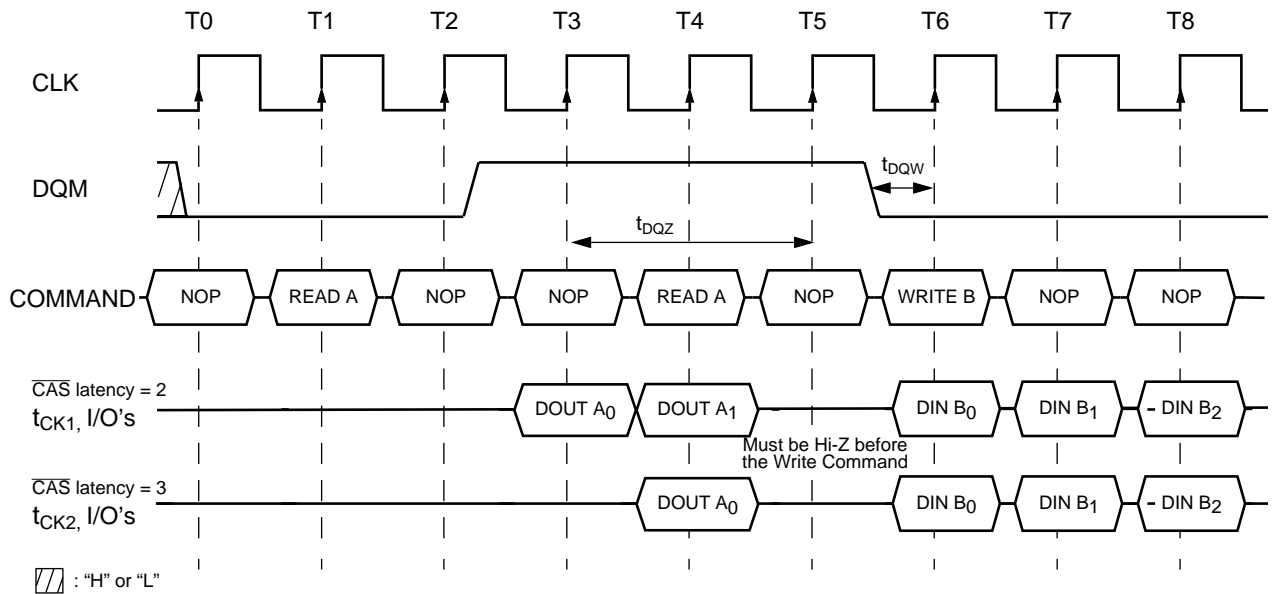
**4.2 Minimum Read to Write Interval**

**(Burst Length = 4, CAS latency = 2)**



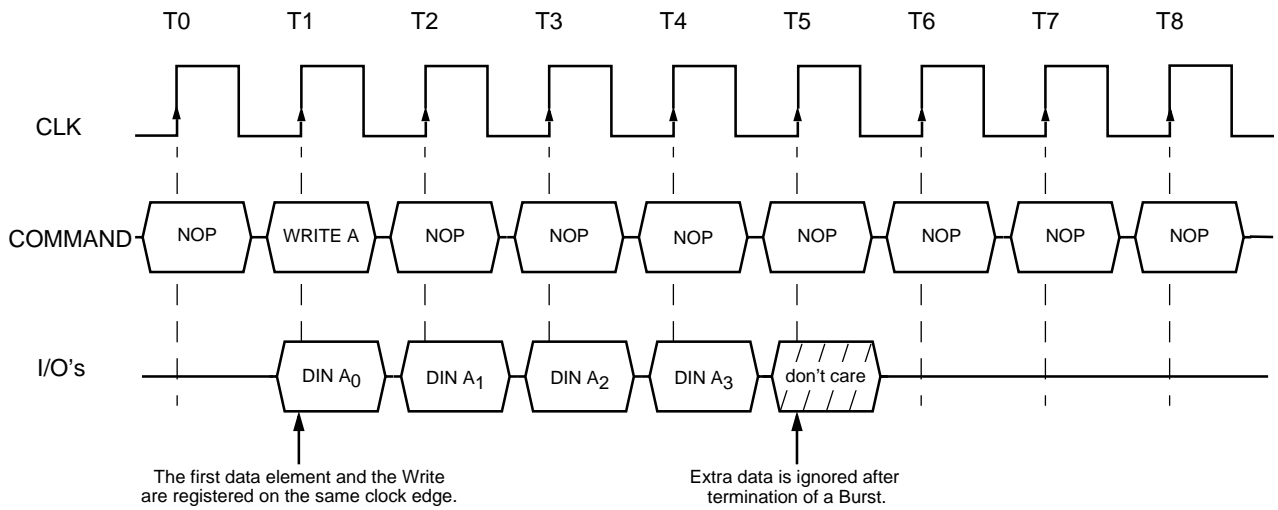
**4.3 Non-Minimum Read to Write Interval**

**(Burst Length = 4, CAS latency = 2, 3)**



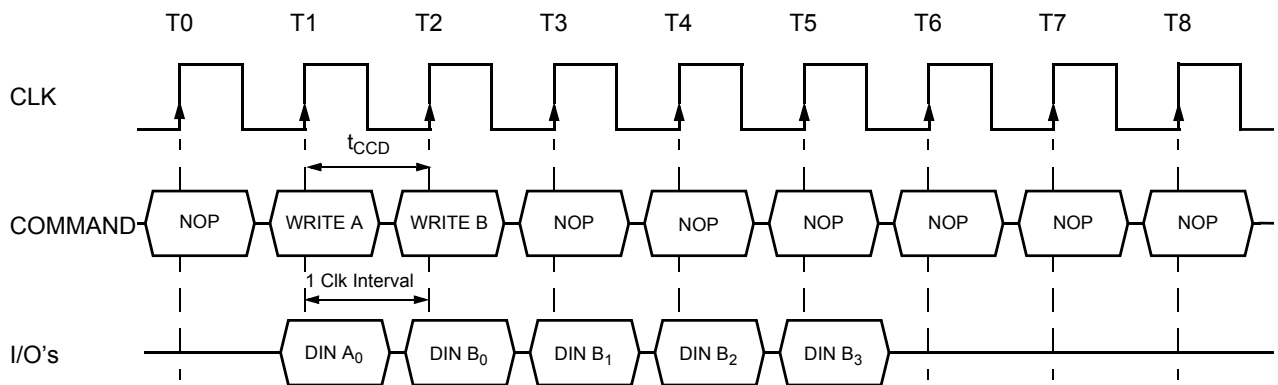
**5. Burst Write Operation**

**(Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2, 3)**



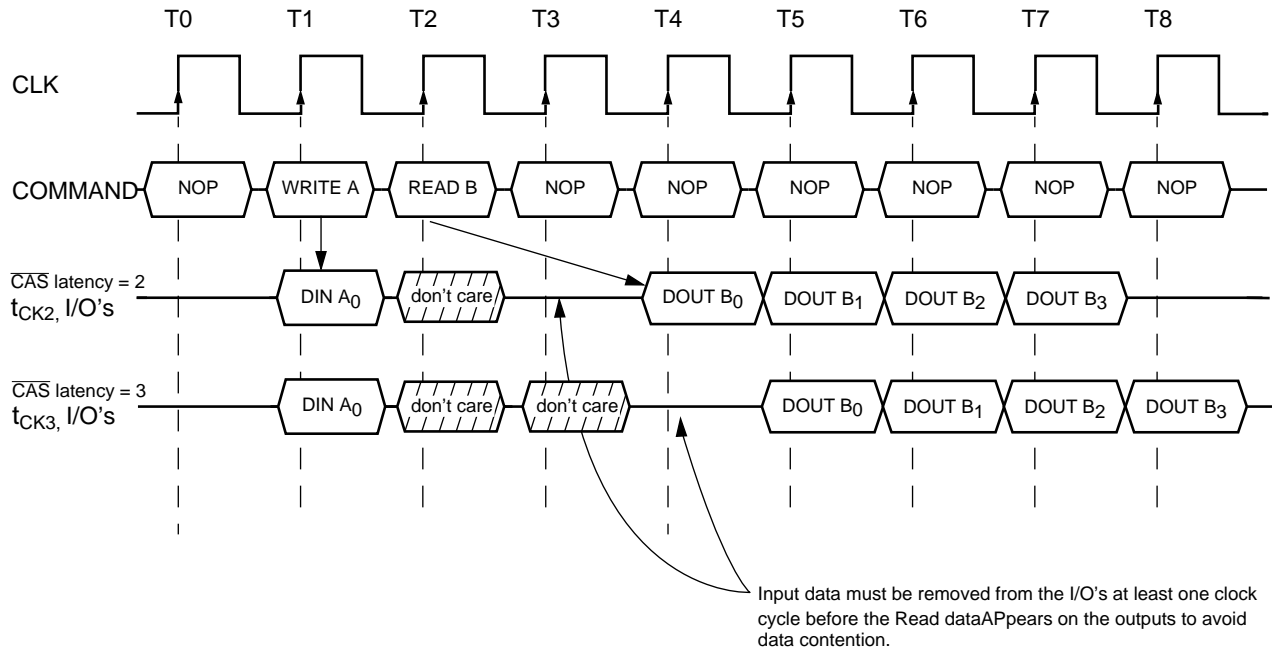
**6.1 Write Interrupted by a Write**

**(Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2, 3)**



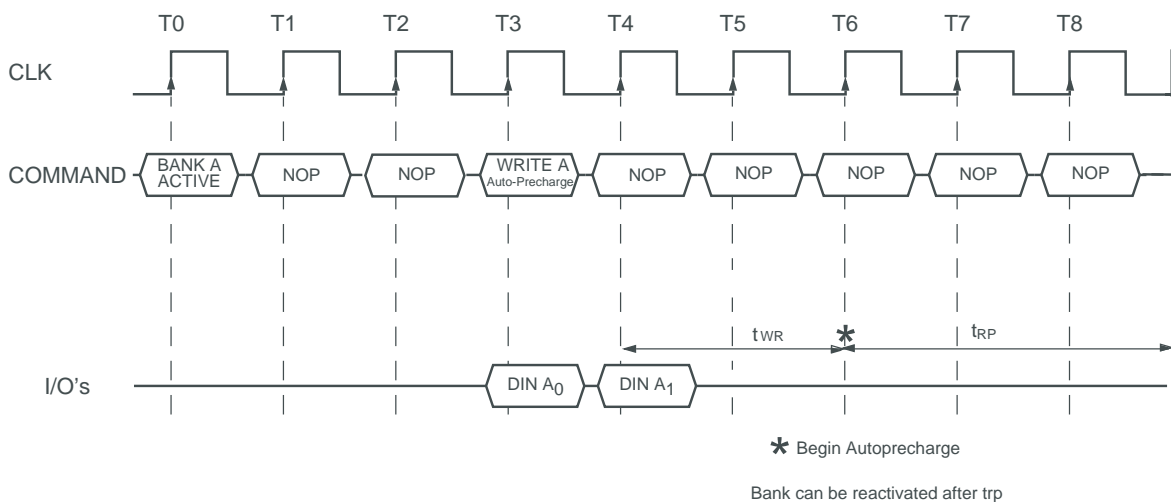
**6.2 Write Interrupted by a Read**

**(Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2, 3)**



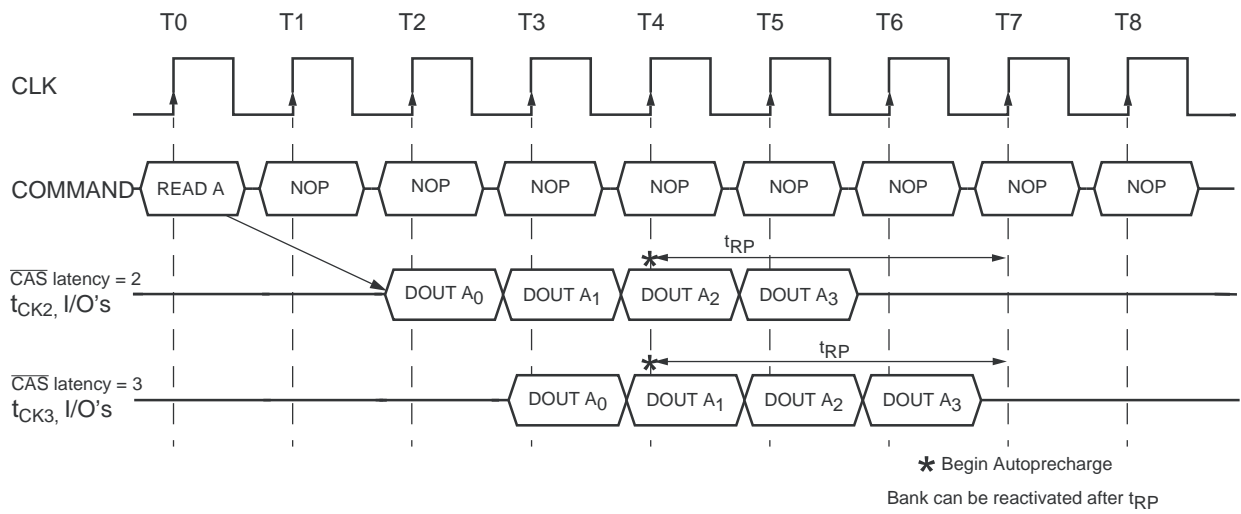
**7. Burst Write with Auto-Precharge**

**Burst Length = 2,  $\overline{\text{CAS}}$  latency = 2, 3)**



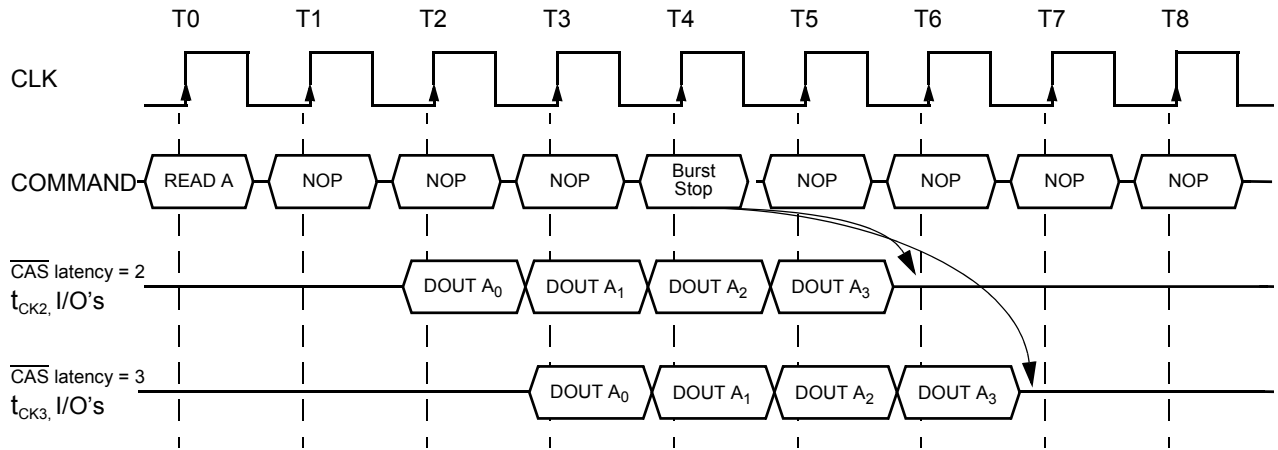
7.2 Burst Read with Auto-Precharge

Burst Length = 4,  $\overline{\text{CAS}}$  latency = 2, 3)



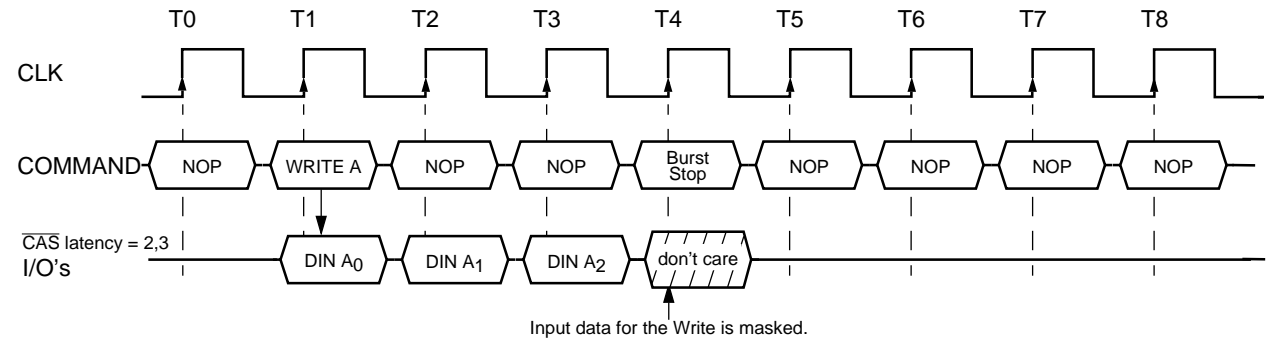
**8.1 Termination of a Burst Read Operation**

( $\overline{\text{CAS}}$  latency = 2, 3)



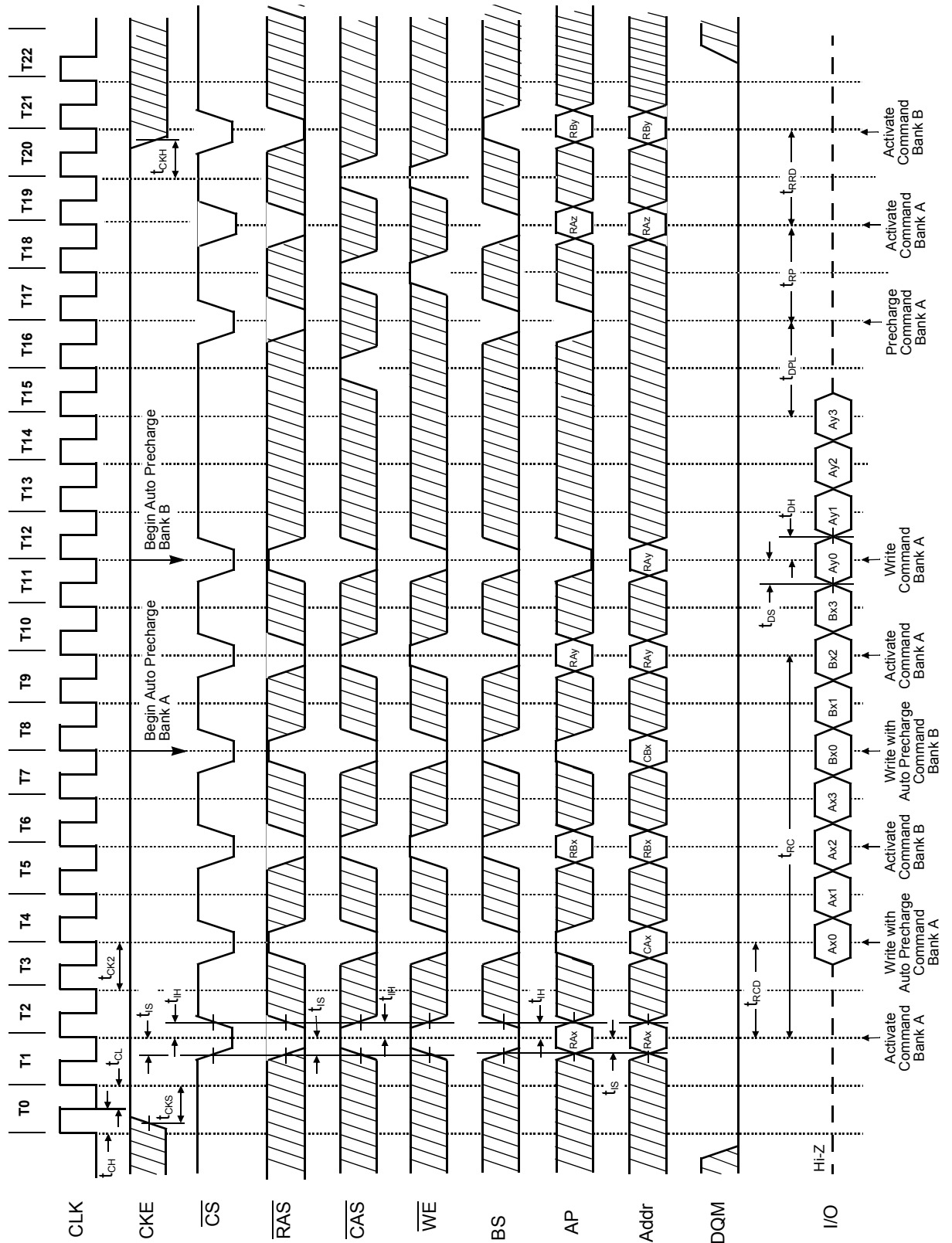
**8.2 Termination of a Burst Write Operation**

( $\overline{\text{CAS}}$  latency = 2, 3)

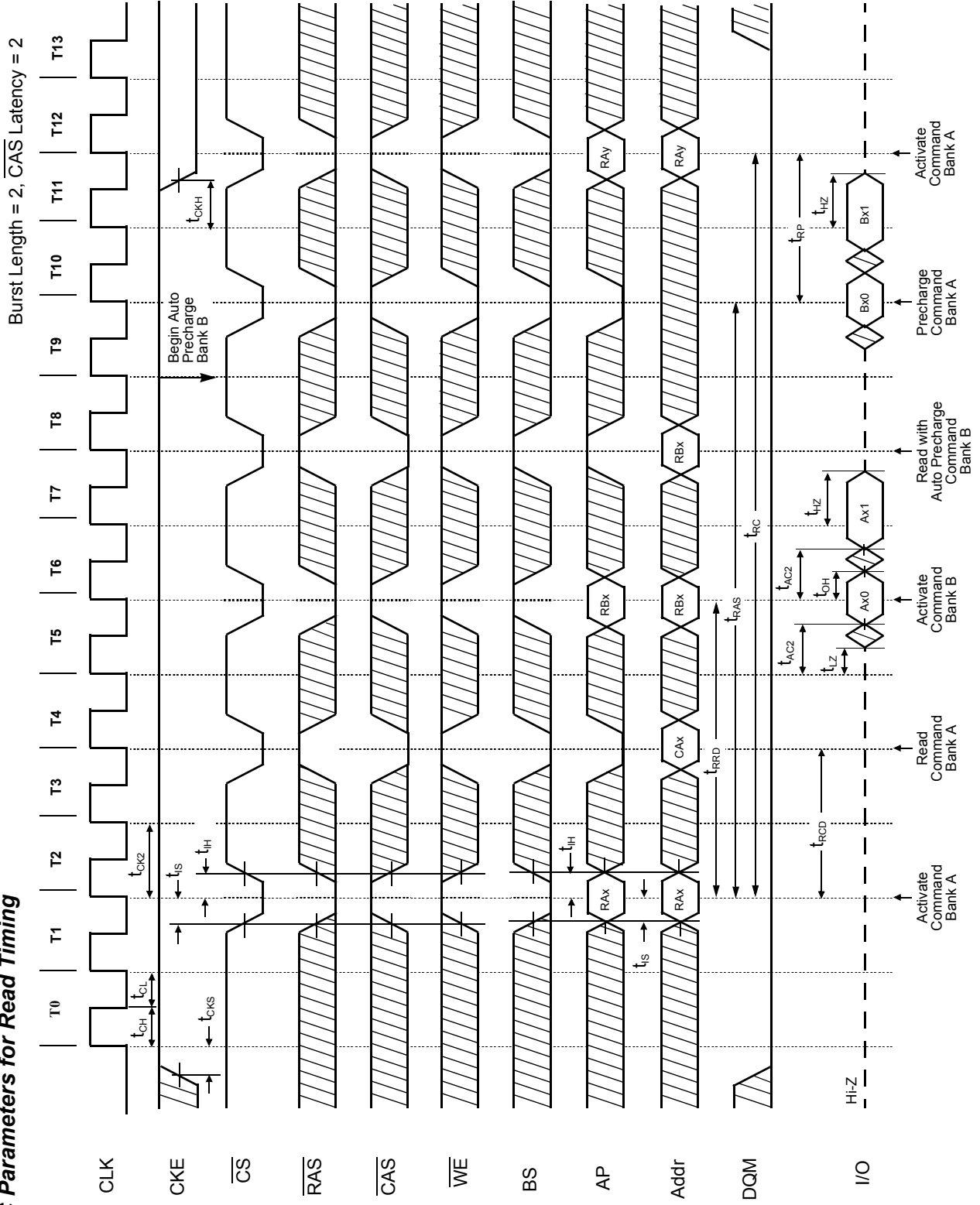


9.1 AC Parameters for Write Timing

Burst Length = 4, CAS Latency = 2

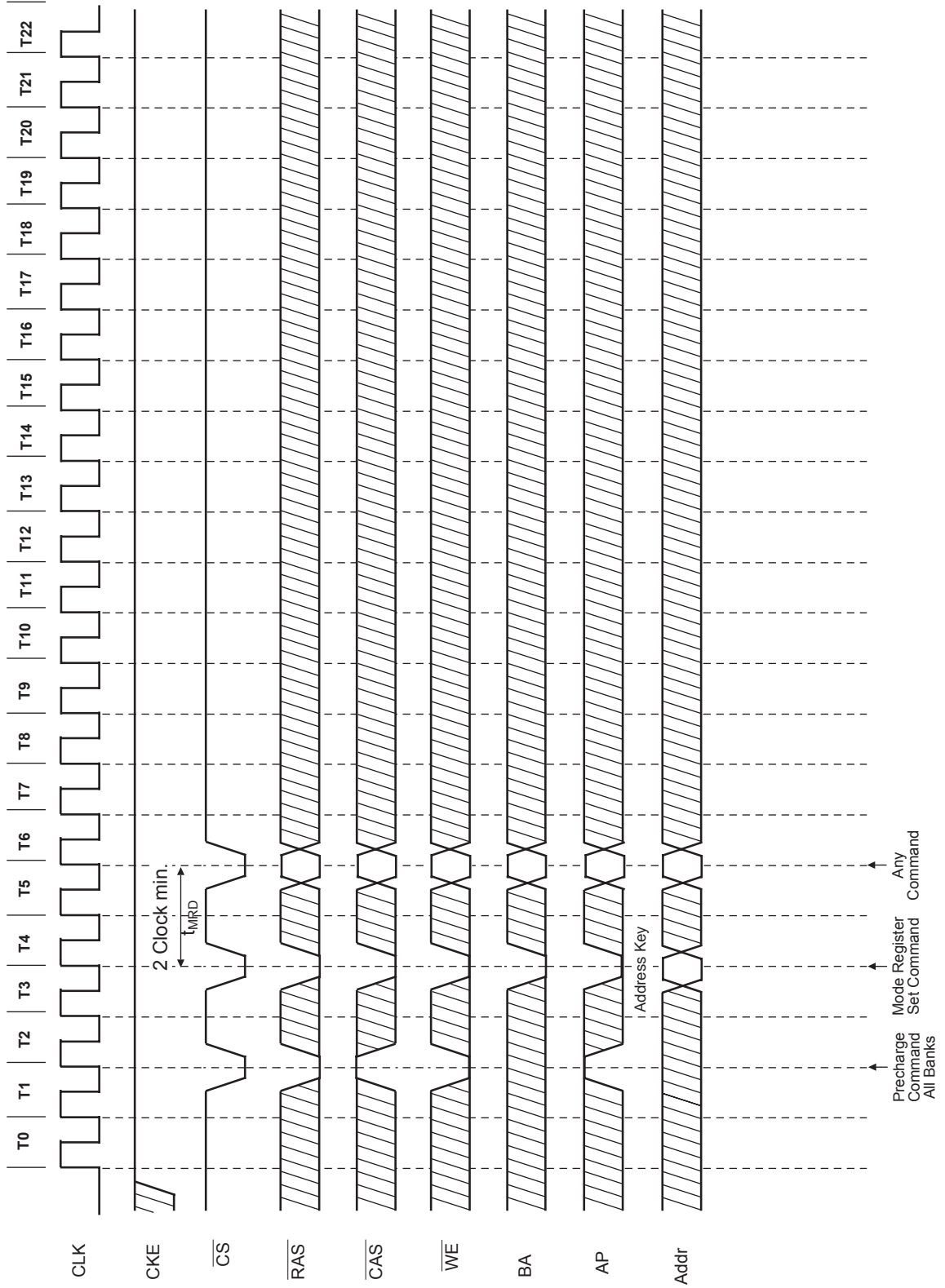


9.2 AC Parameters for Read Timing

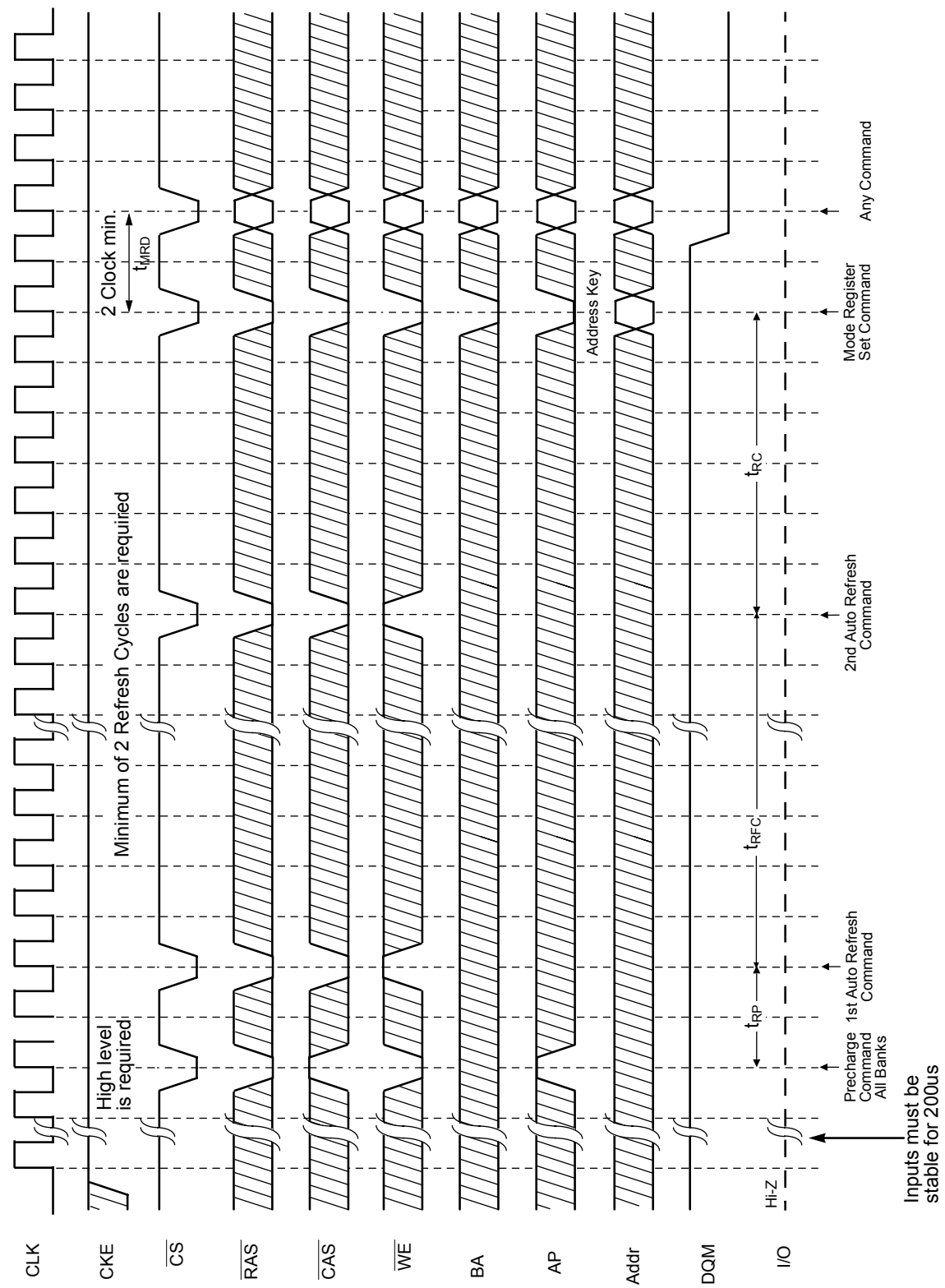




10. Mode Register Set

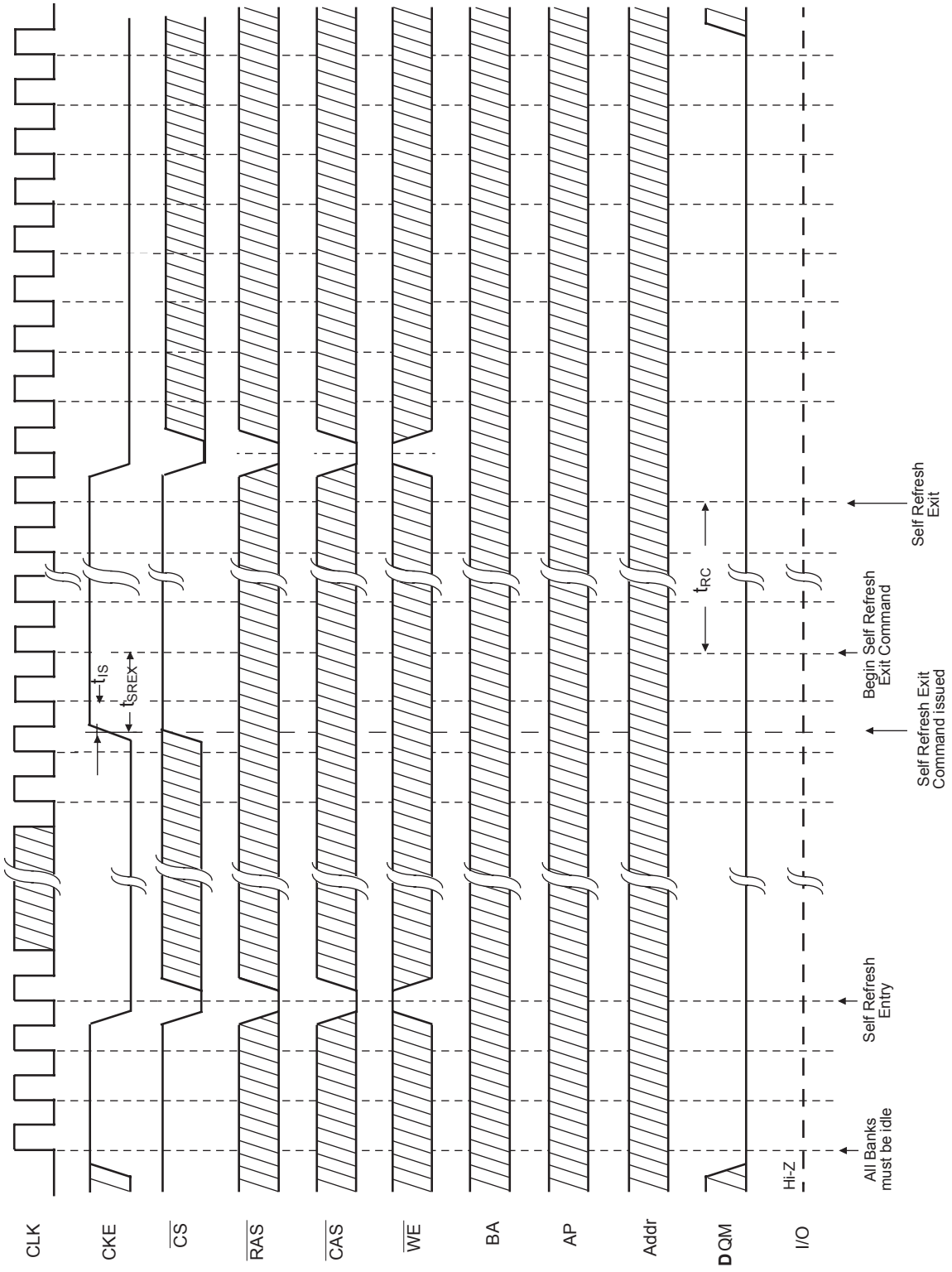


11. Power on Sequence and Auto Refresh (CBR)



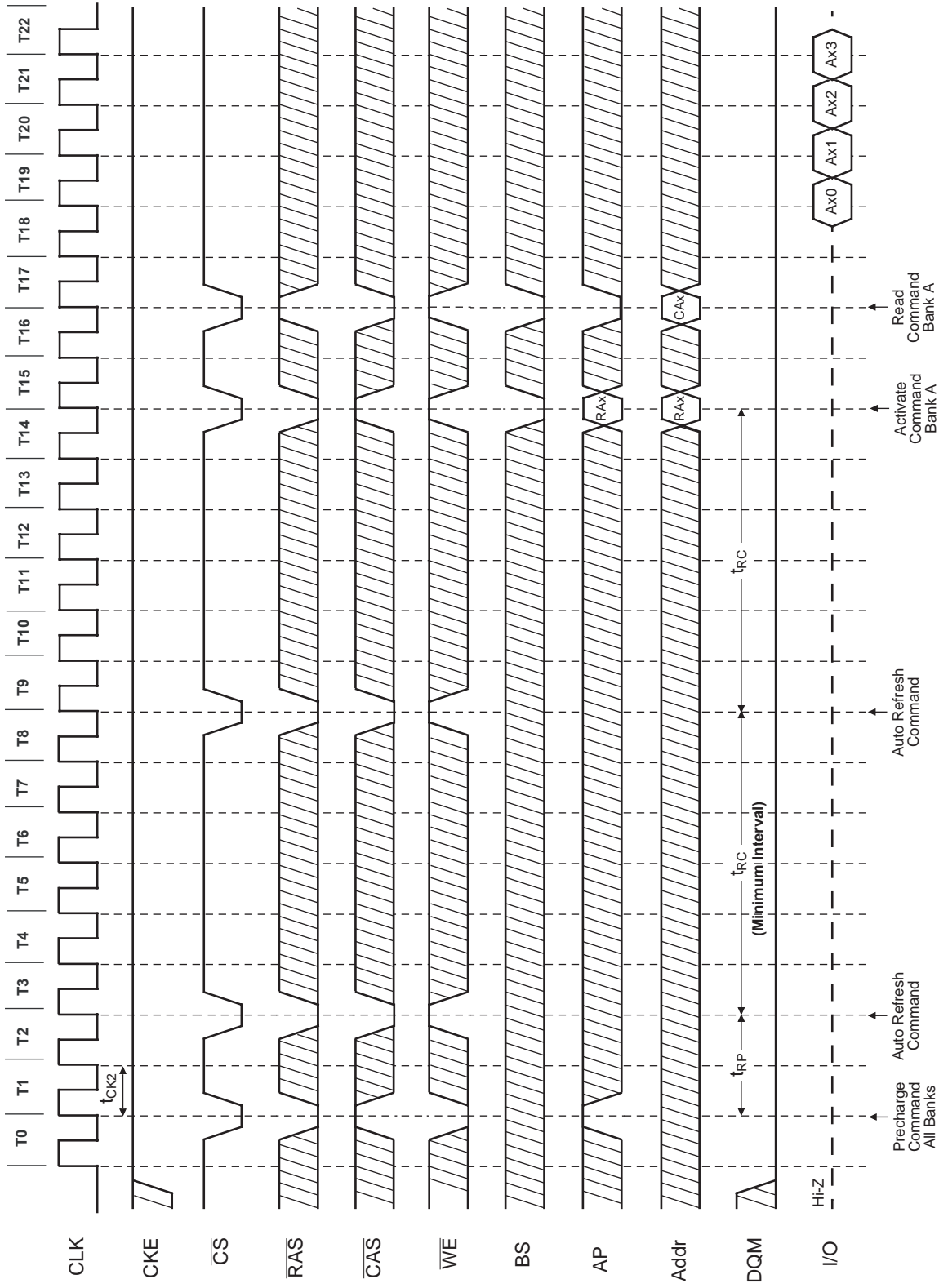


13. Self Refresh (Entry and Exit)



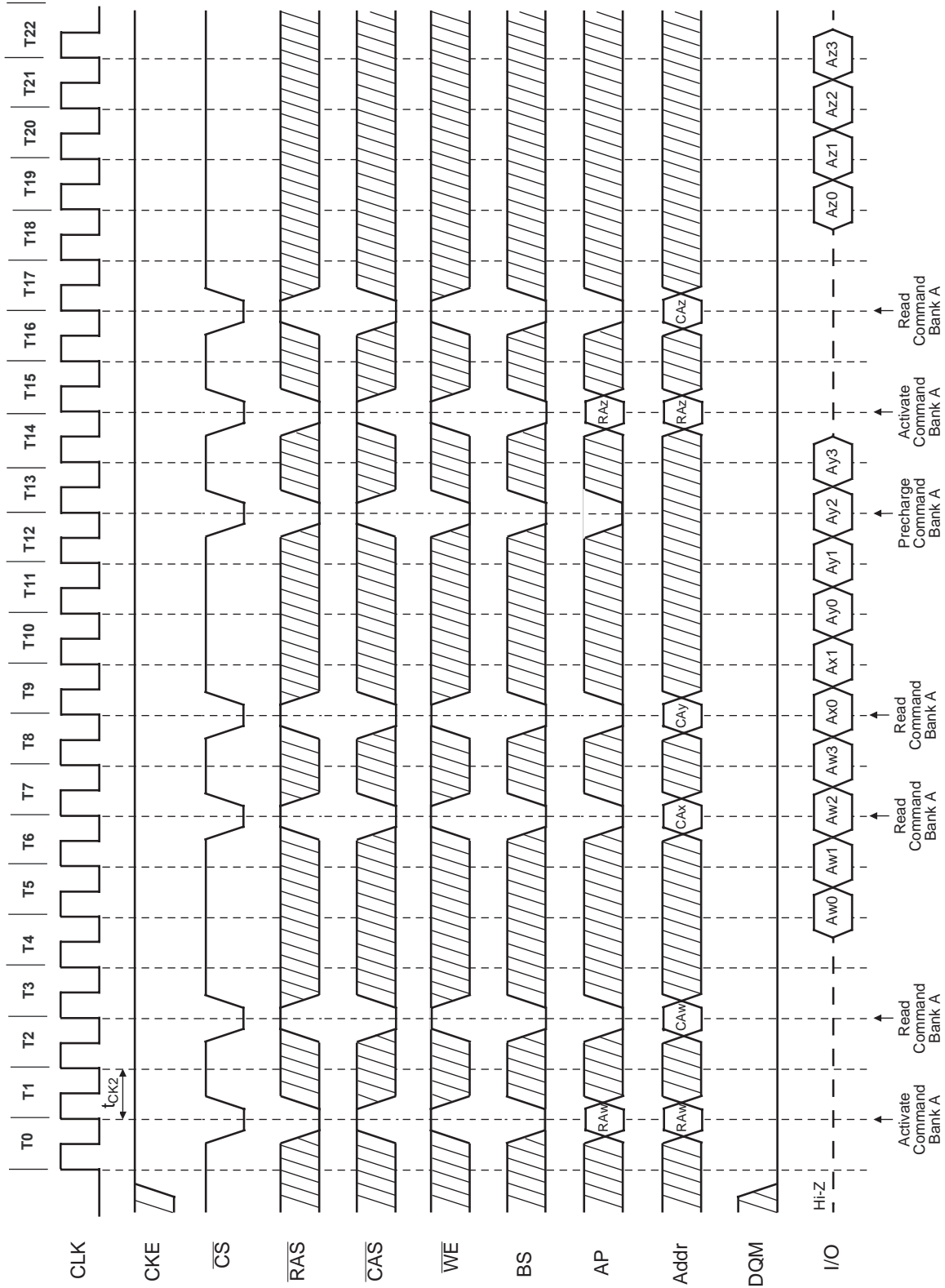
14. Auto Refresh (CBR)

Burst Length = 4, CAS Latency = 2



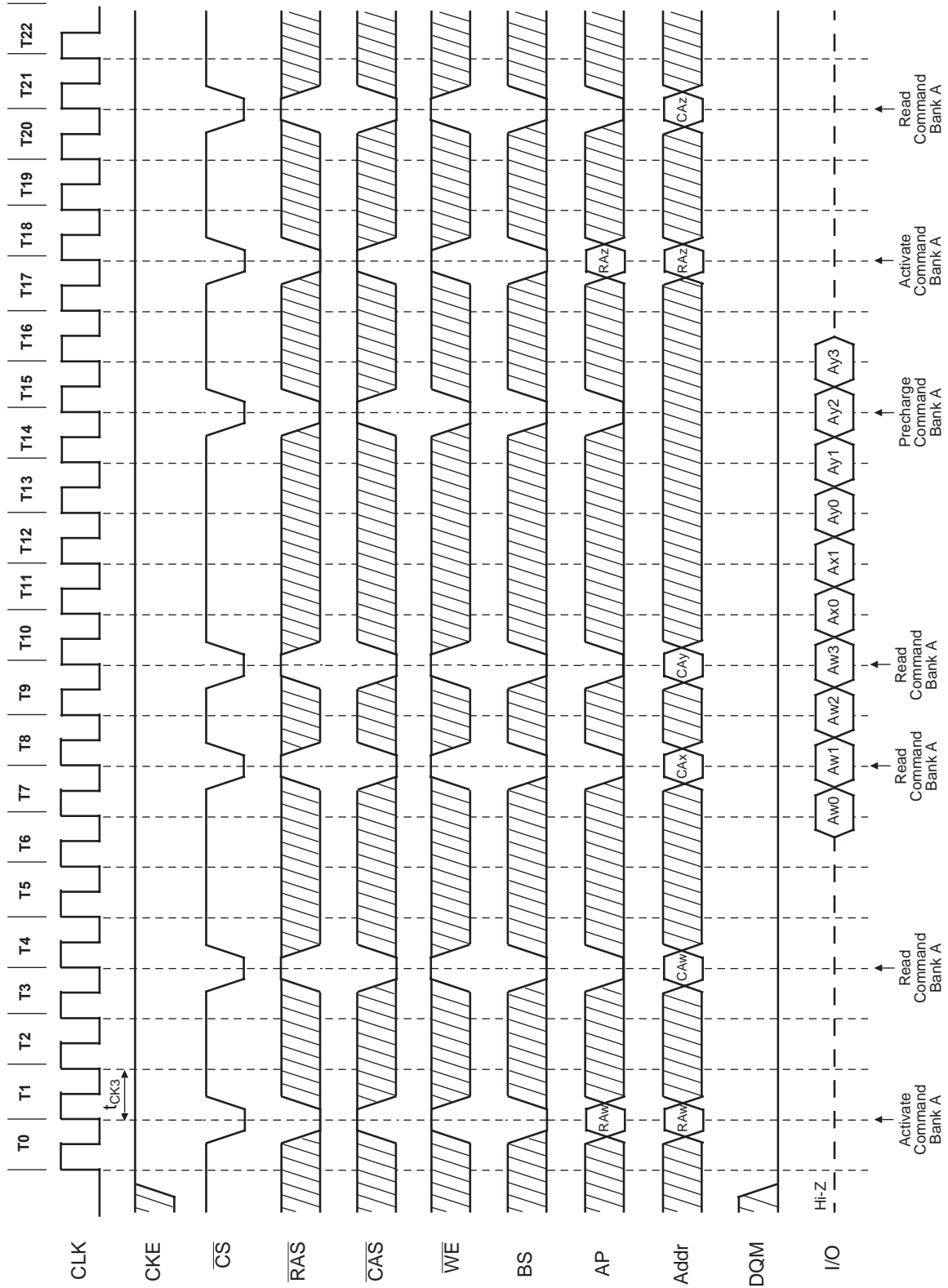
15.1 Random Column Read (Page within same Bank) (1 of 2)

Burst Length = 4, CAS Latency = 2



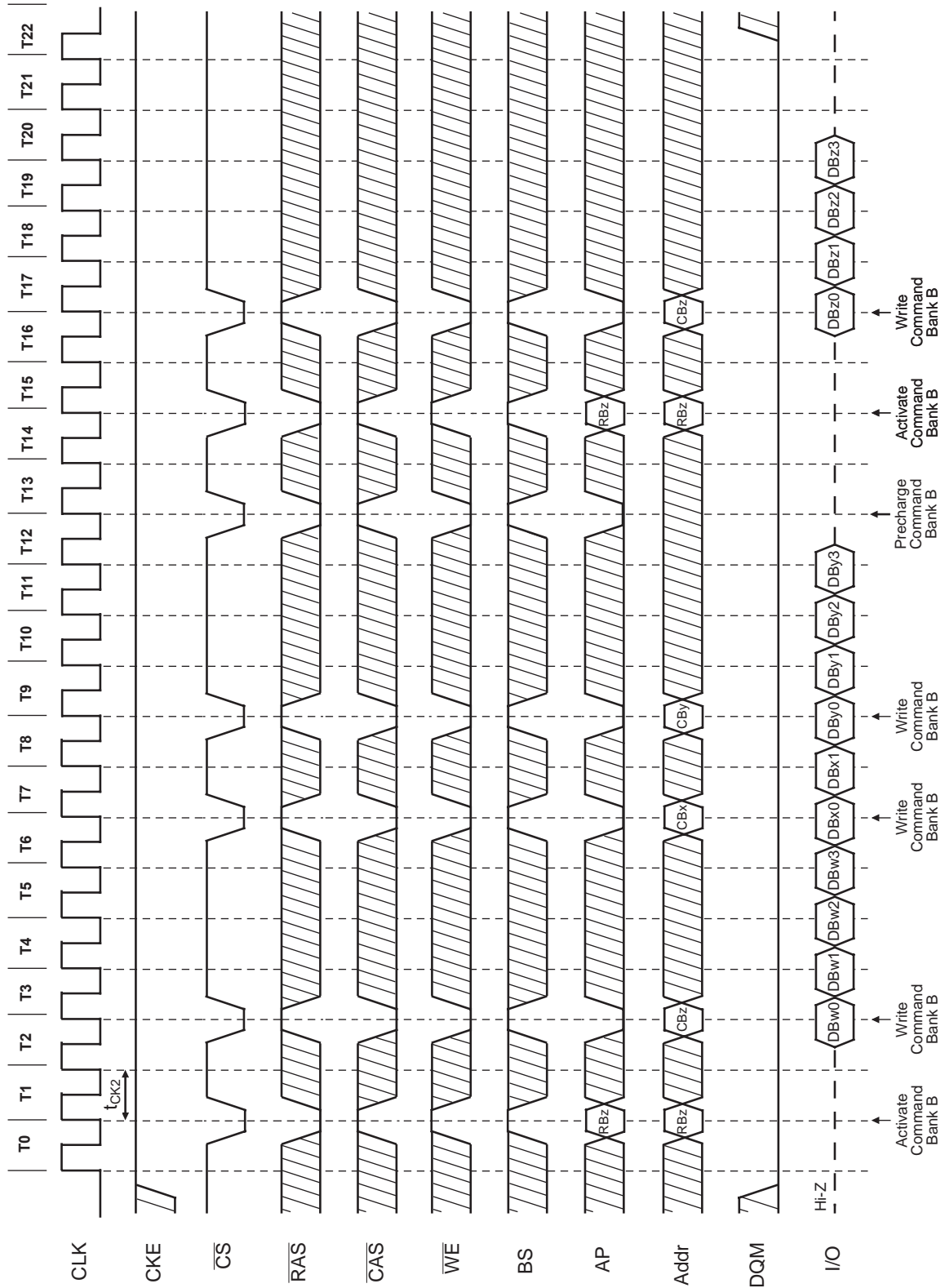
15.2 Random Column Read (Page within same Bank) (2 of 2)

Burst Length = 4, CAS Latency = 3



16.1 Random Column Write (Page within same Bank) (1 of 2)

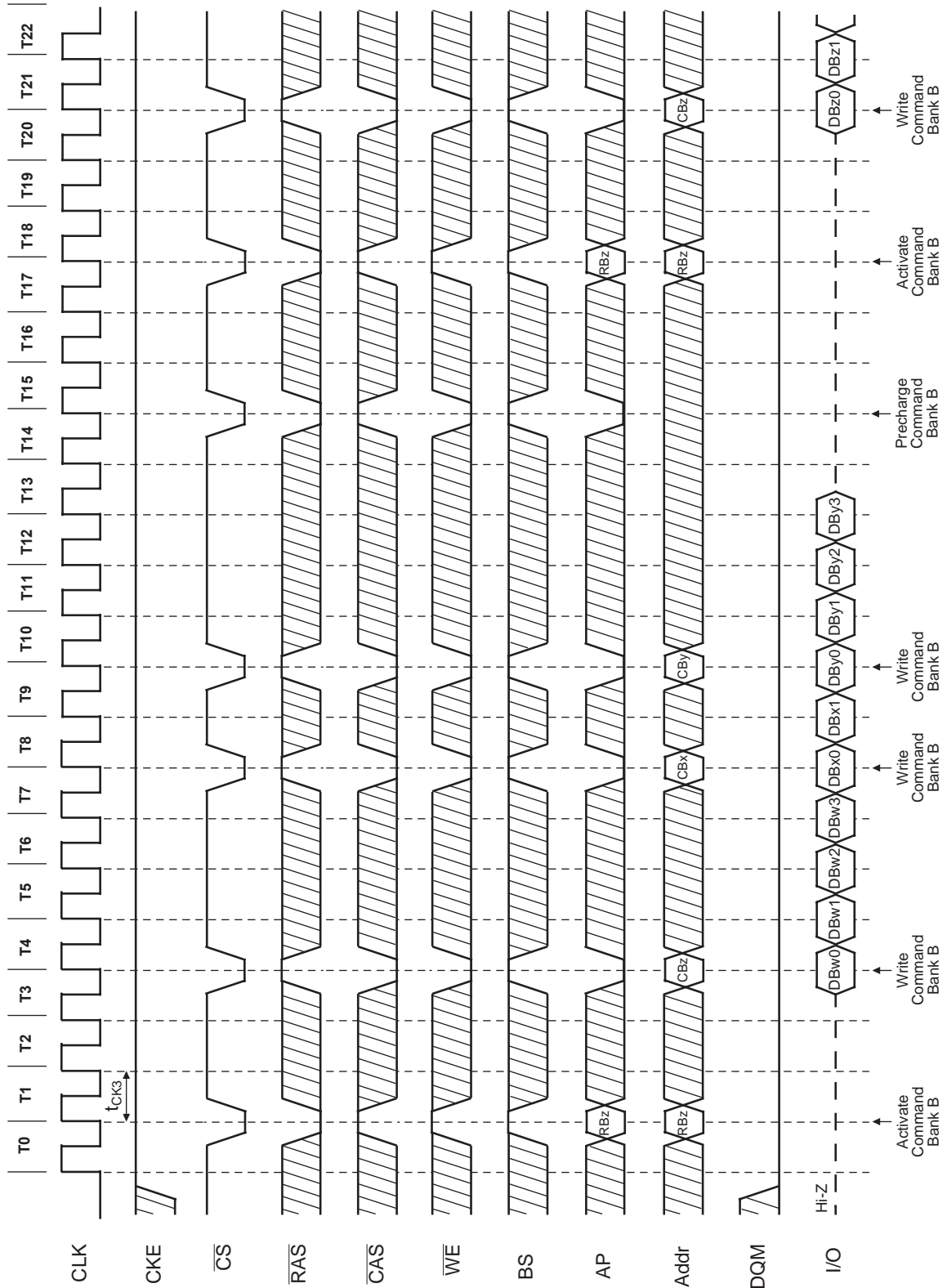
Burst Length = 4, CAS Latency = 2





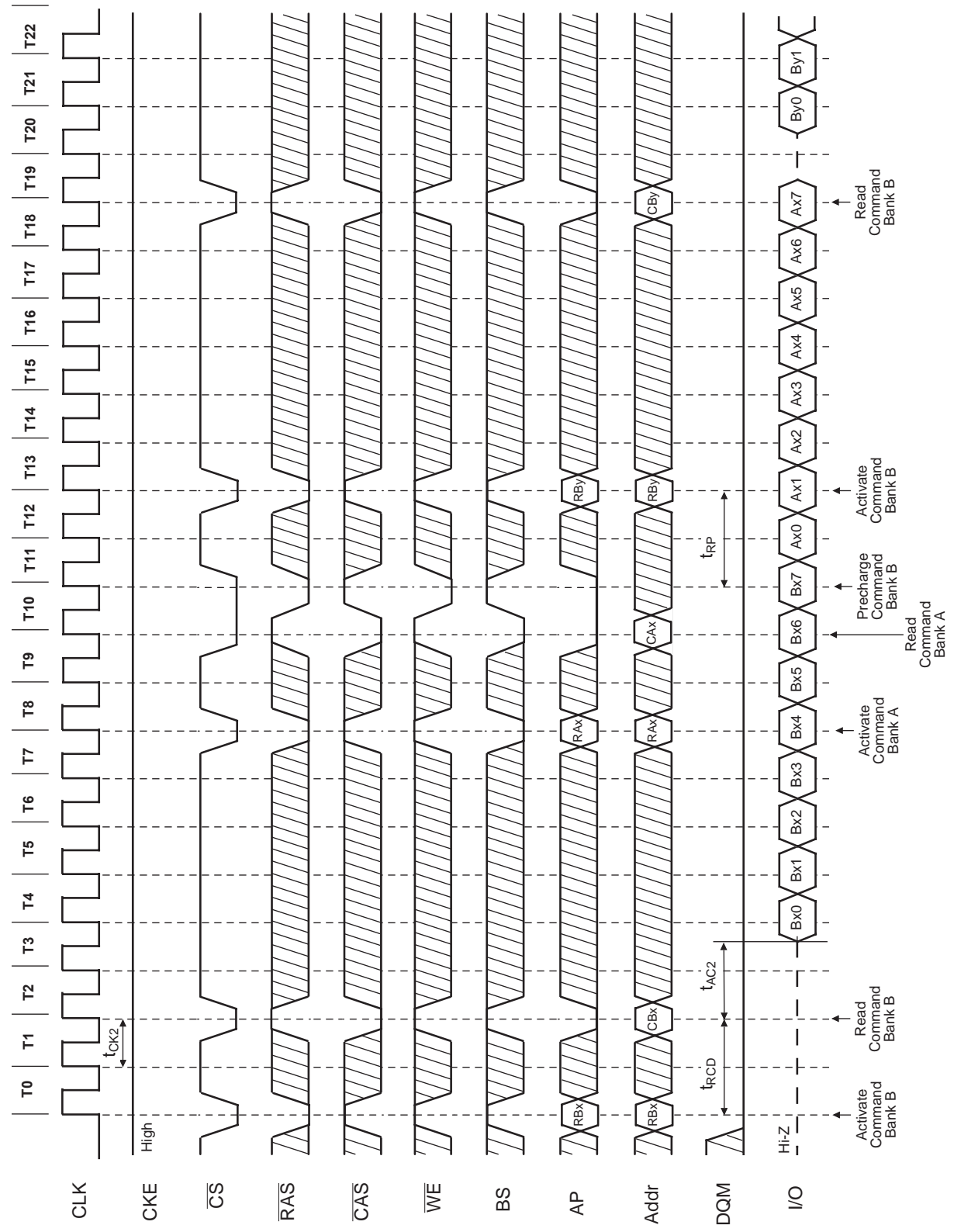
16.2 Random Column Write (Page within same Bank) (2 of 2)

Burst Length = 4, CAS Latency = 3



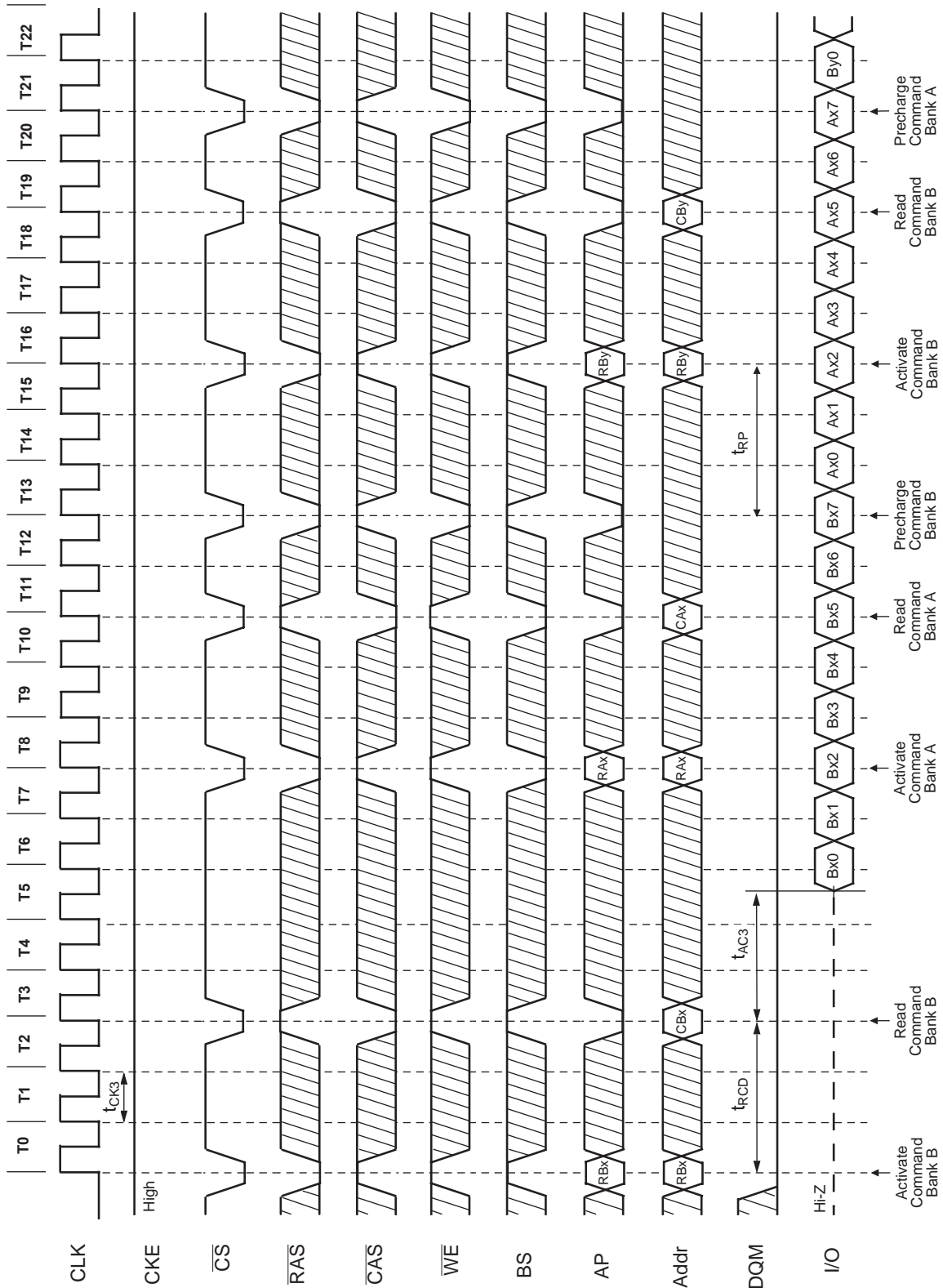
Burst Length = 8, CAS Latency = 2

17.1 Random Row Read (Interleaving Banks) (1 of 2)



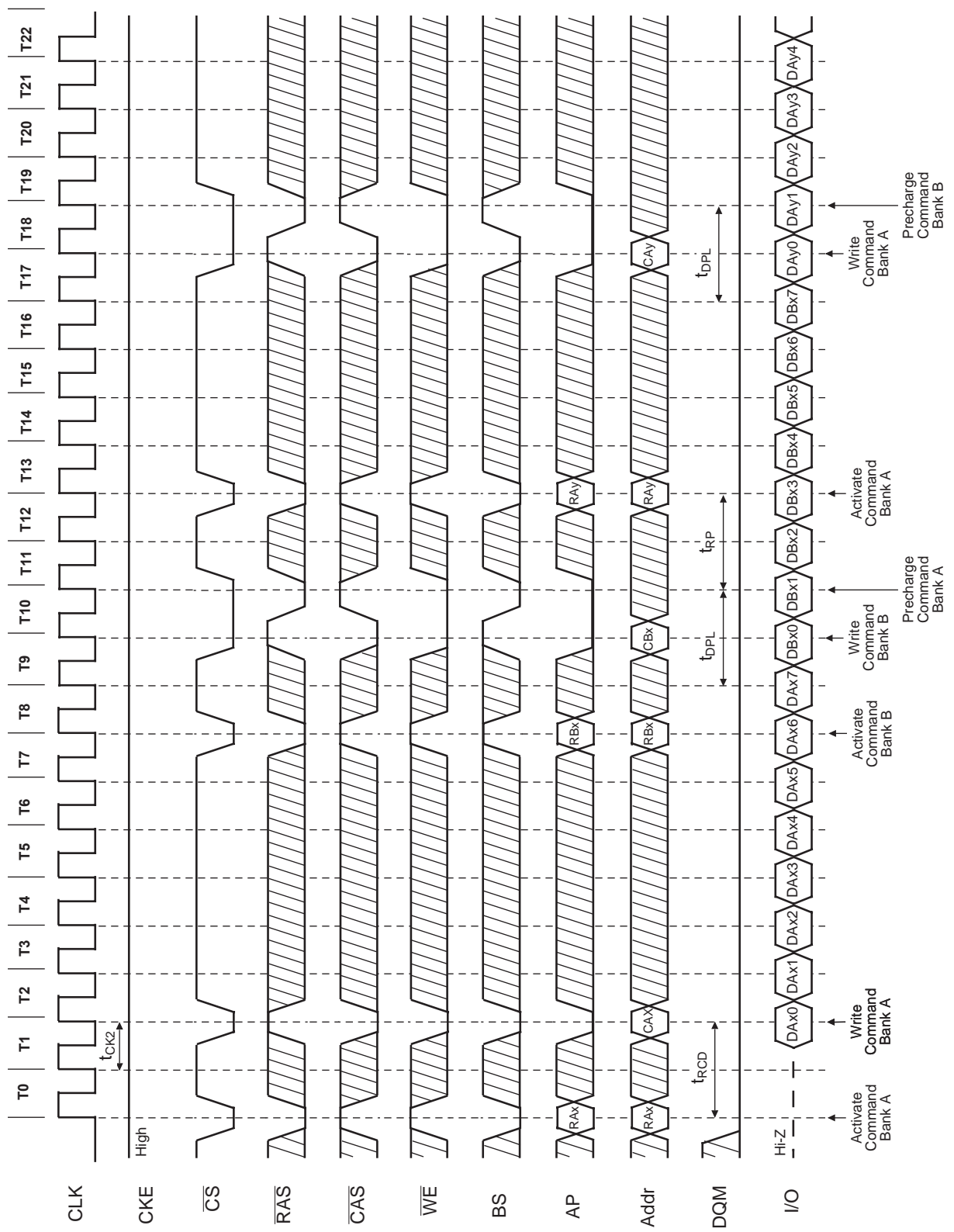
Burst Length = 8, CAS Latency = 3

17.2 Random Row Read (Interleaving Banks) (2 of 2)



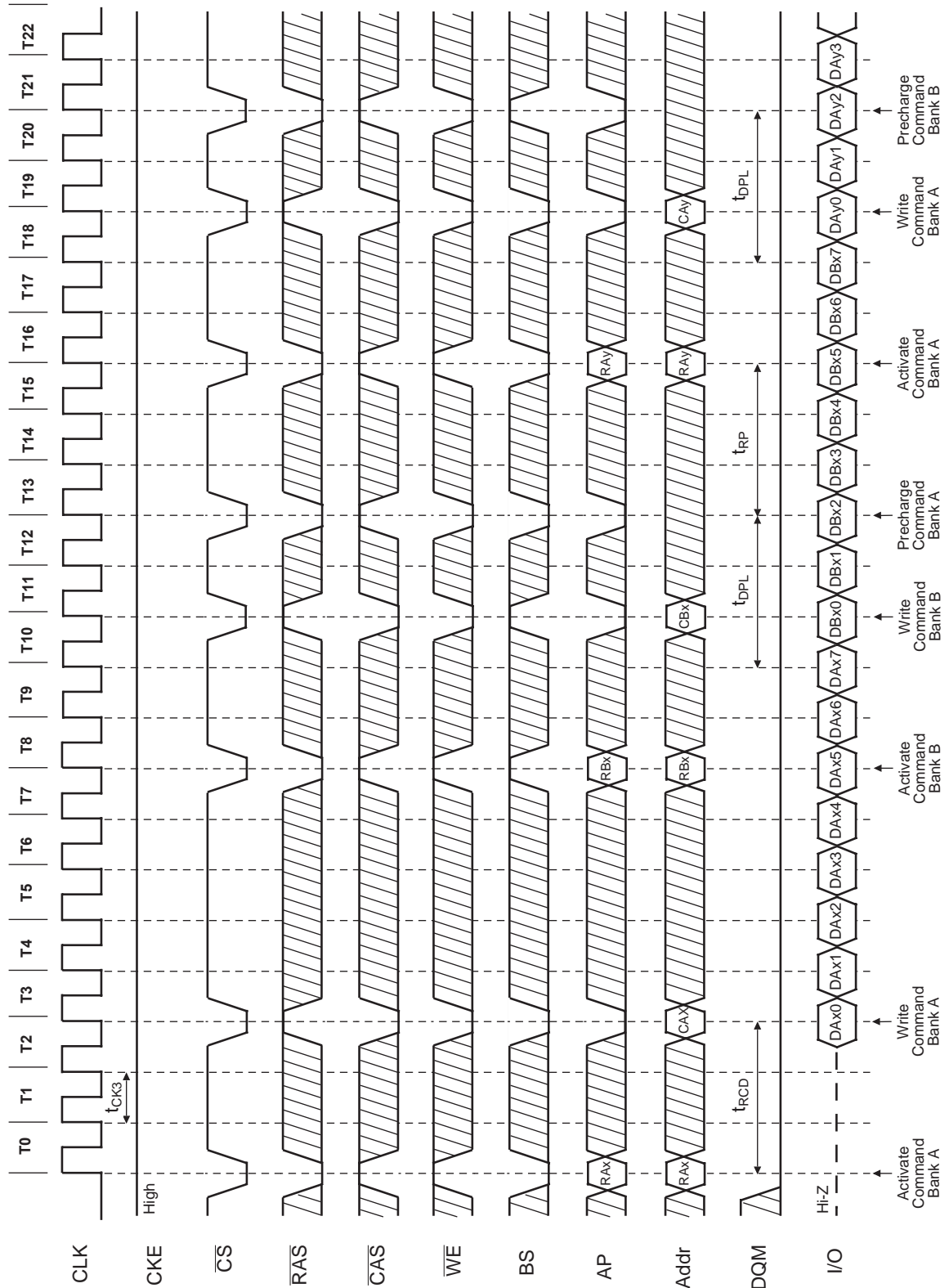
Burst Length = 8, CAS Latency = 2

18.1 Random Row Write (Interleaving Banks) (1 of 2)



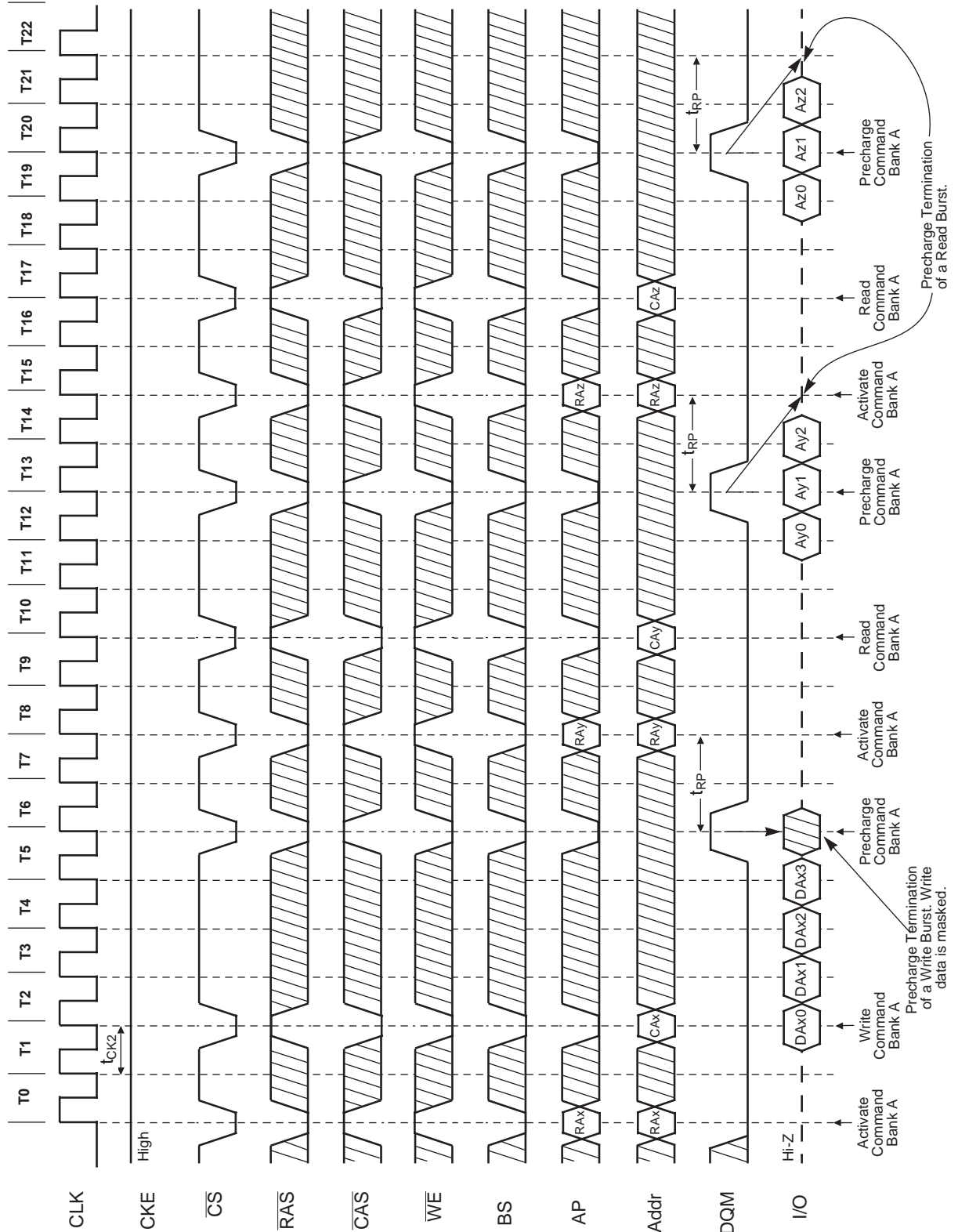
18.2 Random Row Write (Interleaving Banks) (2 of 2)

Burst Length = 8, CAS Latency = 3



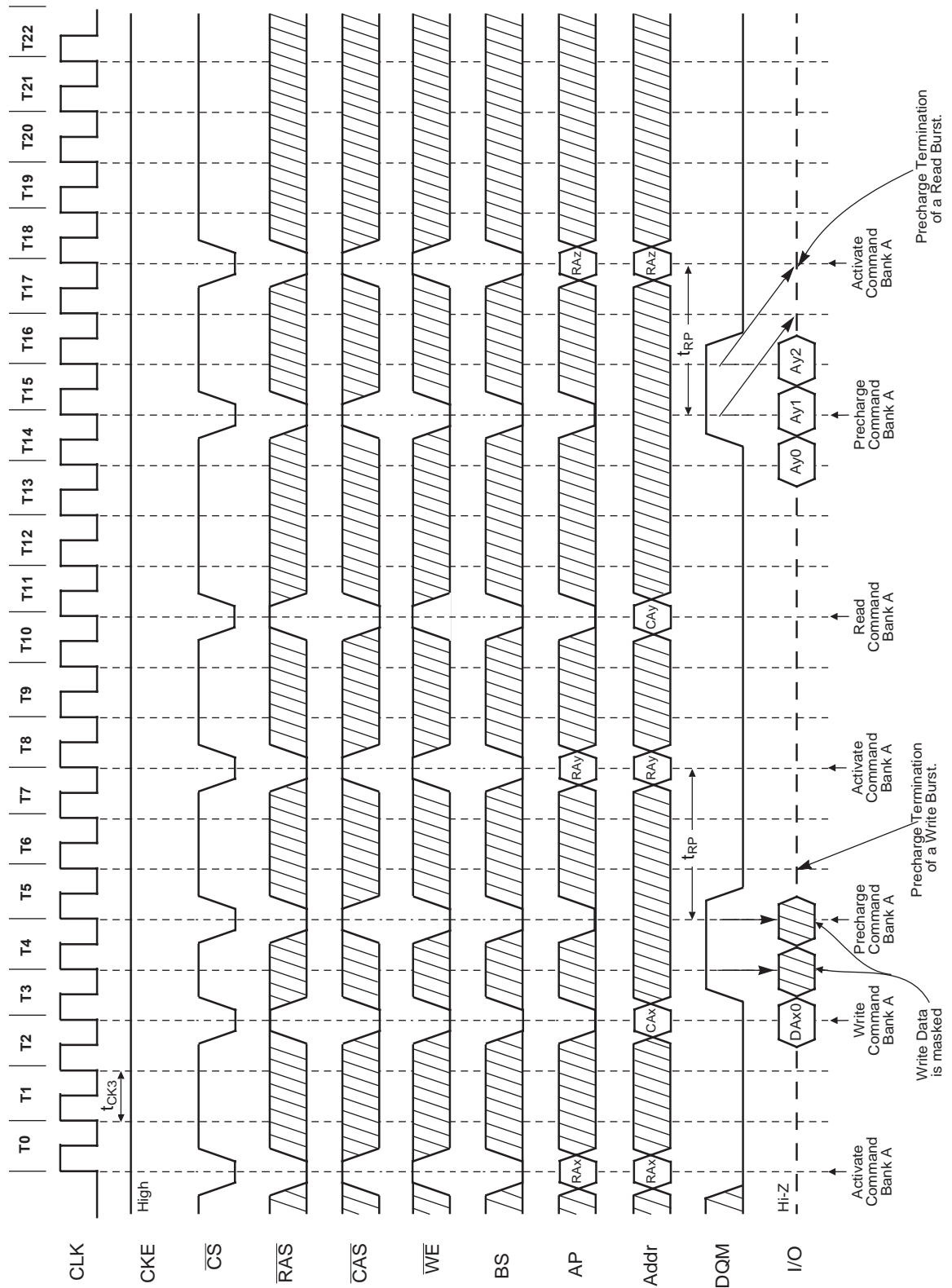
19.1 Precharge Termination of a Burst (1 of 2)

Burst Length = 8, CAS Latency = 2



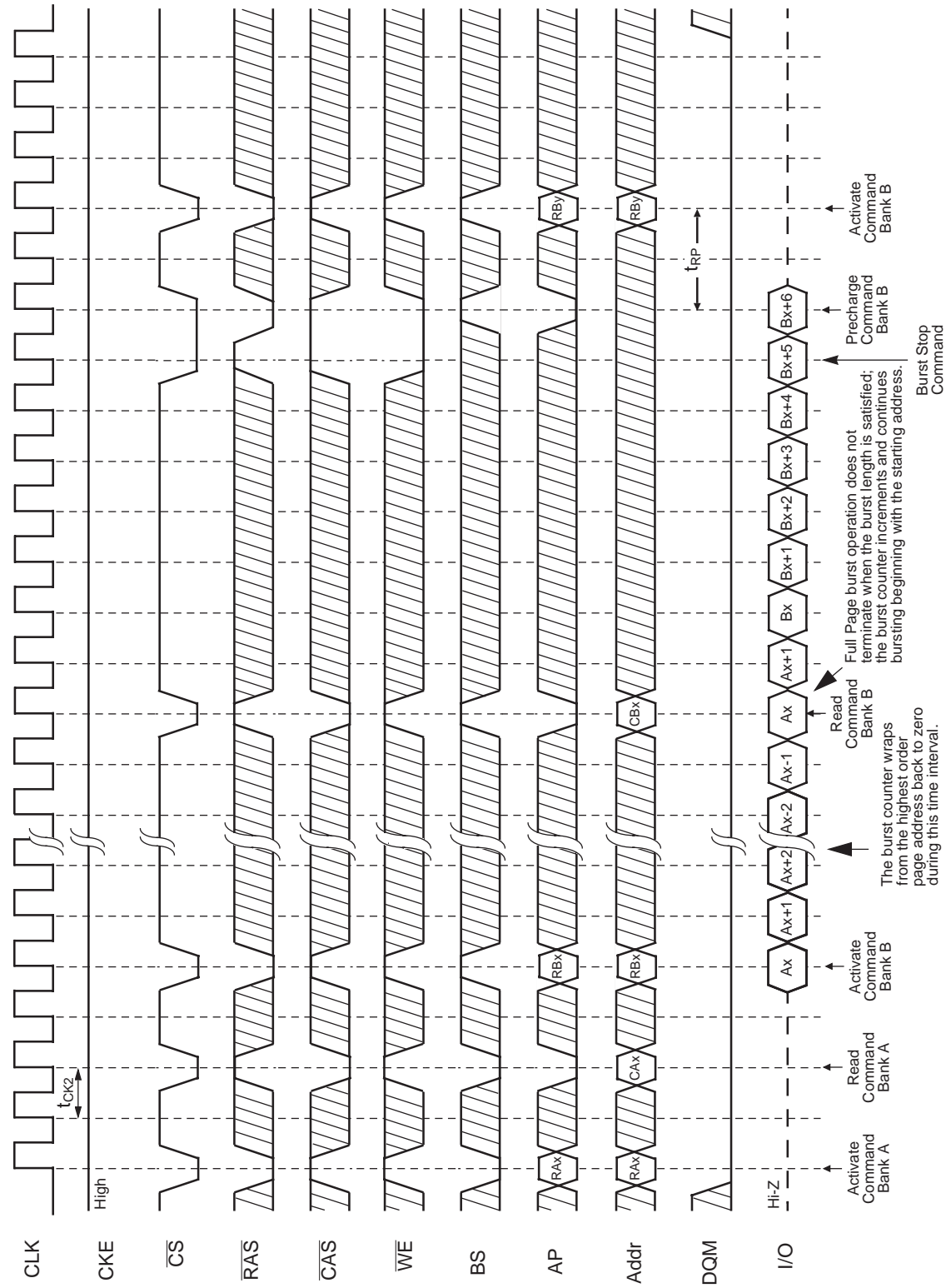
Burst Length = 4, 8, CAS Latency = 3

19.2 Precharge Termination of a Burst (2 of 2)



Burst Length = Full Page, CAS Latency = 2

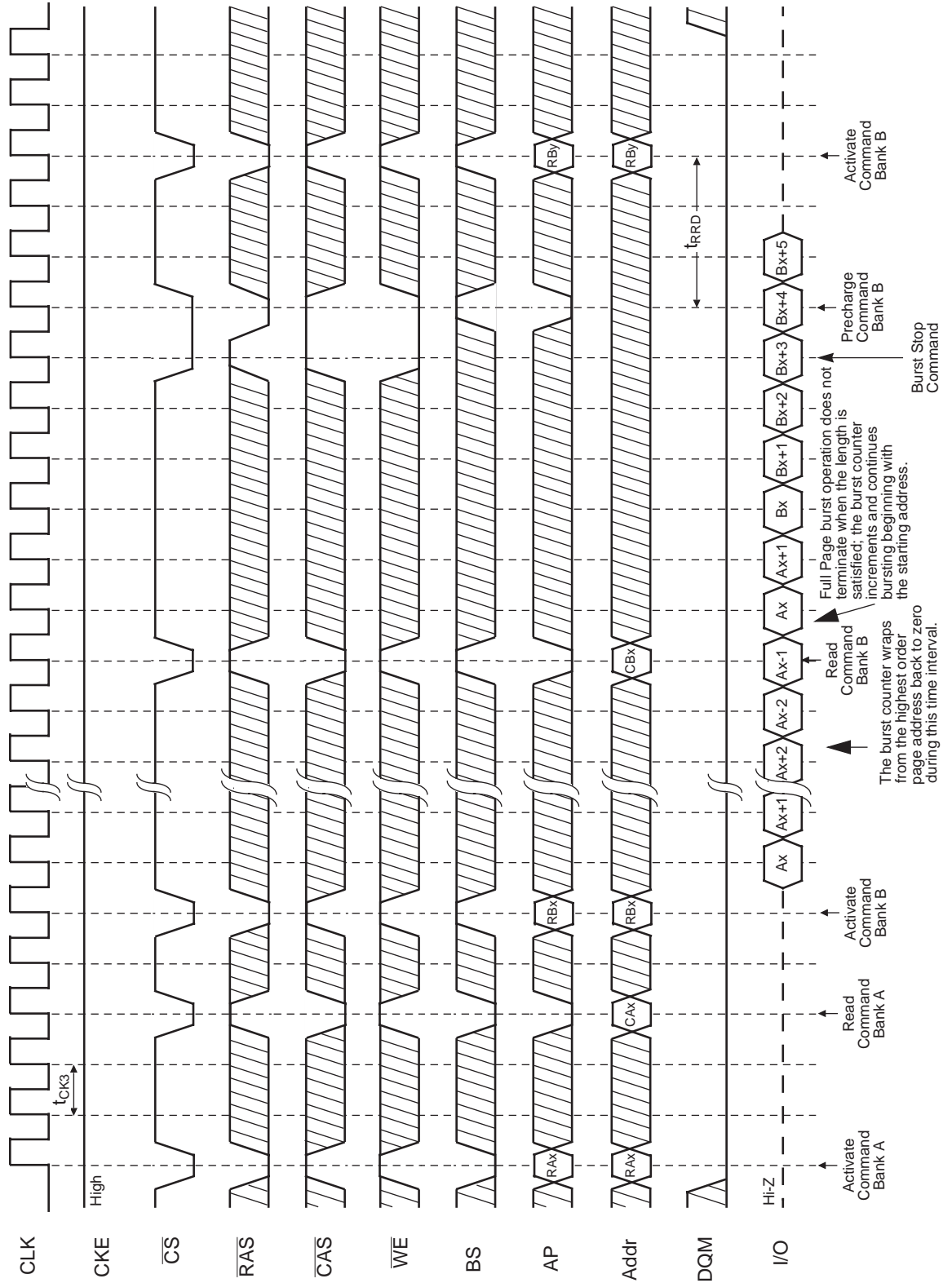
20.1 Full Page Read Cycle (1 of 2)





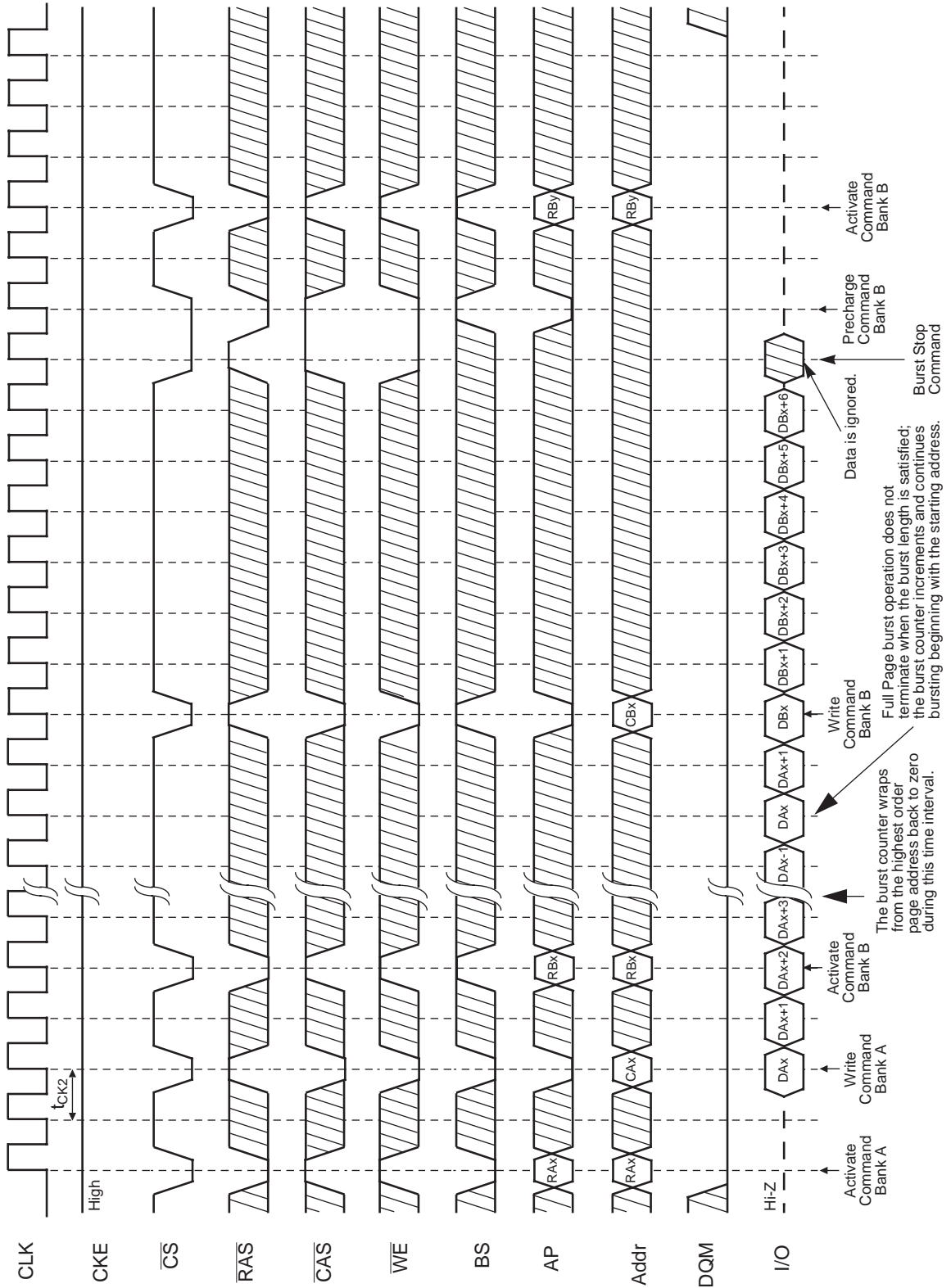
Burst Length = Full Page, CAS Latency = 3

20.2 Full Page Read Cycle (2 of 2)



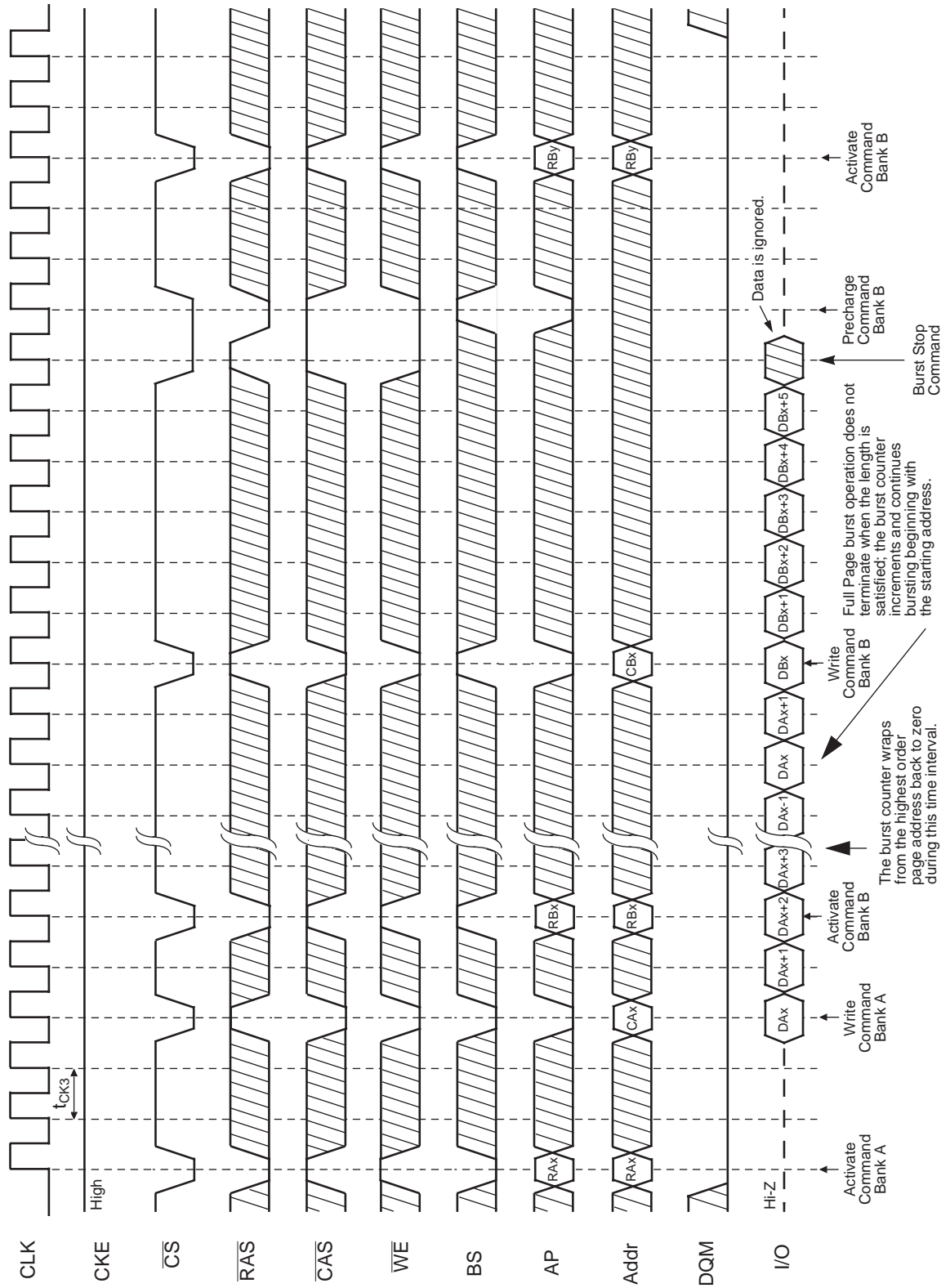
Burst Length = Full Page,  $\overline{\text{CAS}}$  Latency = 2

21.1 Full Page Write Cycle (1 of 2)



Burst Length = Full Page, CAS Latency = 3

21.2 Full Page Write Cycle (2 of 2)



**Complete List of Operation Commands**

**SDRAM Function Truth Table**

CURRENT STATE <sup>1</sup>	$\overline{\text{CS}}$	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{WE}}$	BS	Addr	ACTION
Idle	H	X	X	X	X	X	NOP or Power Down
	L	H	H	H	X	X	NOP
	L	H	H	L	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	X	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	H	BS	RA	Row (&Bank) Active; Latch Row Address
	L	L	H	L	BS	AP	NOP <sup>4</sup>
	L	L	L	H	X	X	Auto-Refresh or Self-Refresh <sup>5</sup>
	L	L	L	L	Op-	Code	Mode reg. Access <sup>5</sup>
Row Active	H	X	X	X	X	X	NOP
	L	H	H	X	X	X	NOP
	L	H	L	H	BS	CA,AP	Begin Read; Latch CA; DetermineAP
	L	H	L	L	BS	CA,AP	Begin Write; Latch CA; DetermineAP
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	Precharge
	L	L	L	X	X	X	ILLEGAL
Read	H	X	X	X	X	X	NOP (Continue Burst to End;>Row Active)
	L	H	H	H	X	X	NOP (Continue Burst to End;>Row Active)
	L	H	H	L	BS	X	Burst Stop Command > Row Active
	L	H	L	H	BS	CA,AP	Term Burst, New Read, DetermineAP <sup>3</sup>
	L	H	L	L	BS	CA,AP	Term Burst, Start Write, DetermineAP <sup>3</sup>
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	Term Burst, Precharge
	L	L	L	X	X	X	ILLEGAL
Write	H	X	X	X	X	X	NOP (Continue Burst to End;>Row Active)
	L	H	H	H	X	X	NOP (Continue Burst to End;>Row Active)
	L	H	H	L	BS	X	Burst Stop Command > Row Active
	L	H	L	H	BS	CA,AP	Term Burst, Start Read, DetermineAP <sup>3</sup>
	L	H	L	L	BS	CA,AP	Term Burst, New Write, DetermineAP <sup>3</sup>
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	Term Burst, Precharge <sup>3</sup>
	L	L	L	X	X	X	ILLEGAL
Read with Auto Precharge	H	X	X	X	X	X	NOP (Continue Burst to End;> Precharge)
	L	H	H	H	X	X	NOP (Continue Burst to End;> Precharge)
	L	H	H	L	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	H	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	L	X	X	ILLEGAL
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	ILLEGAL <sup>2</sup>
	L	L	L	X	X	X	ILLEGAL

**SDRAM Function Truth Table (continued)**

CURRENT STATE <sup>1</sup>	$\overline{\text{CS}}$	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{WE}}$	BS	Addr	ACTION
Write with Auto Precharge	H	X	X	X	X	X	NOP (Continue Burst to End;> Precharge)
	L	H	H	H	X	X	NOP (Continue Burst to End;> Precharge)
	L	H	H	L	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	H	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	L	X	X	ILLEGAL
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	ILLEGAL <sup>2</sup>
L	L	L	X	X	X	ILLEGAL	
Precharging	H	X	X	X	X	X	NOP;> Idle after tRP
	L	H	H	H	X	X	NOP;> Idle after tRP
	L	H	H	L	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	X	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	NOP <sup>4</sup>
	L	L	L	X	X	X	ILLEGAL
Row Activating	H	X	X	X	X	X	NOP;> Row Active after tRCD
	L	H	H	H	X	X	NOP;> Row Active after tRCD
	L	H	H	L	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	X	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	ILLEGAL <sup>2</sup>
	L	L	L	X	X	X	ILLEGAL
Write Recovering	H	X	X	X	X	X	NOP
	L	H	H	H	X	X	NOP
	L	H	H	L	BS	X	ILLEGAL <sup>2</sup>
	L	H	L	X	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	H	BS	X	ILLEGAL <sup>2</sup>
	L	L	H	L	BS	AP	ILLEGAL <sup>2</sup>
	L	L	L	X	X	X	ILLEGAL
Refreshing	H	X	X	X	X	X	NOP;> Idle after tRC
	L	H	H	H	X	X	NOP;> Idle after tRC
	L	H	H	L	X	X	ILLEGAL
	L	H	L	X	X	X	ILLEGAL
	L	L	H	X	X	X	ILLEGAL
	L	L	L	X	X	X	ILLEGAL
	L	L	L	X	X	X	ILLEGAL
Mode Register Accessing	H	X	X	X	X	X	NOP
	L	H	H	H	X	X	NOP
	L	H	H	L	X	X	ILLEGAL
	L	H	L	X	X	X	ILLEGAL
	L	L	X	X	X	X	ILLEGAL

**Clock Enable (CKE) Truth Table:**

STATE(n)	CKE n-1	CKE n	$\overline{CS}$	$\overline{RAS}$	$\overline{CAS}$	$\overline{WE}$	Addr	ACTION
Self-Refresh <sup>6</sup>	H	X	X	X	X	X	X	INVALID
	L	H	H	X	X	X	X	EXIT Self-Refresh, Idle after tRC
	L	H	L	H	H	H	X	EXIT Self-Refresh, Idle after tRC
	L	H	L	H	H	L	X	ILLEGAL
	L	H	L	H	L	X	X	ILLEGAL
	L	H	L	L	X	X	X	ILLEGAL
	L	L	X	X	X	X	X	NOP (Maintain Self-Refresh)
Power-Down	H	X	X	X	X	X	X	INVALID
	L	H	H	X	X	X	X	EXIT Power-Down, > Idle.
	L	H	L	H	H	H	X	EXIT Power-Down, > Idle.
	L	H	L	H	H	L	X	ILLEGAL
	L	H	L	H	L	X	X	ILLEGAL
	L	H	L	L	X	X	X	ILLEGAL
	L	L	X	X	X	X	X	NOP (Maintain Low-Power Mode)
All. Banks Idle <sup>7</sup>	H	H	X	X	X	X	X	Refer to the function truth table
	H	L	H	X	X	X	X	Enter Power- Down
	H	L	L	H	H	H	X	Enter Power- Down
	H	L	L	H	H	L	X	ILLEGAL
	H	L	L	H	L	X	X	ILLEGAL
	H	L	L	L	H	X	X	ILLEGAL
	H	L	L	L	L	H	X	Enter Self-Refresh
	H	L	L	L	L	L	X	ILLEGAL
	L	L	X	X	X	X	X	NOP

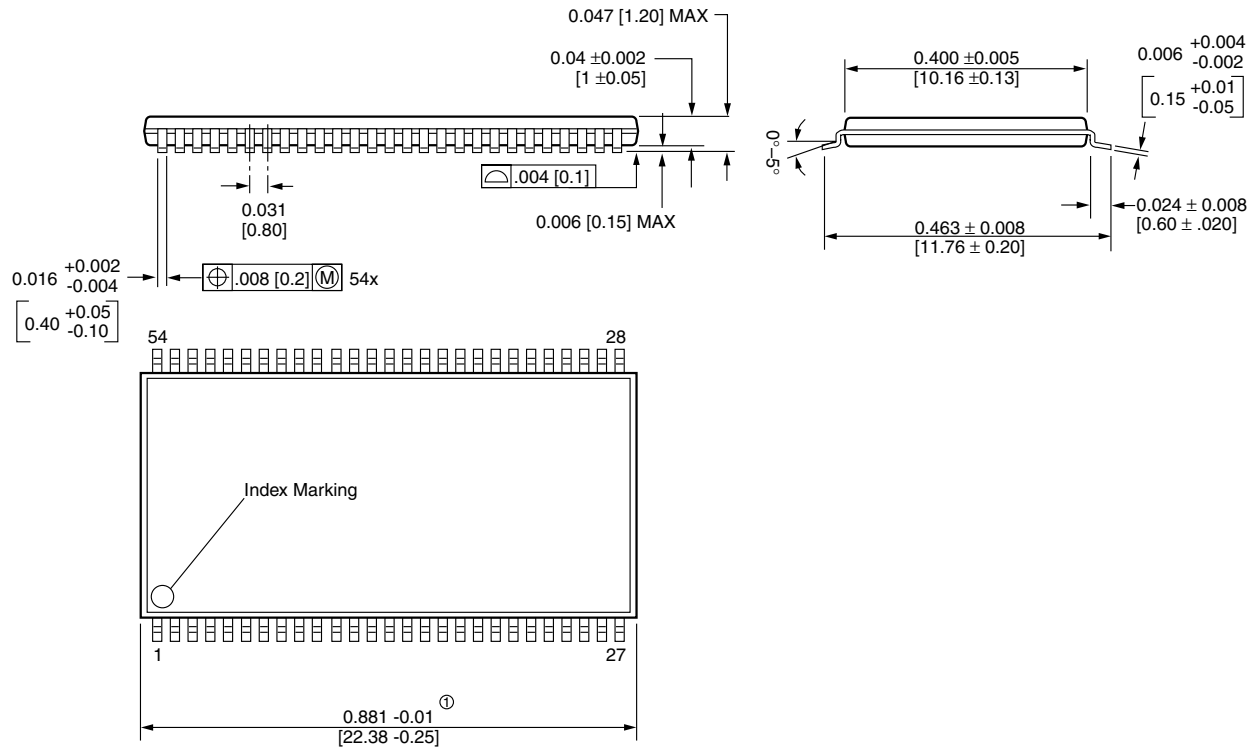
**Abbreviations:**

RA = Row Address of Bank A      CA = Column Address of Bank A      BS = Bank Address  
 RB = Row Address of Bank B      CB = Column Address of Bank B      AP = Auto Precharge  
 RC = Row Address of Bank C      CC = Column Address of Bank C  
 RD = Row Address of Bank D      CD = Column Address of Bank D

**Notes for SDRAM function truth table:**

1. Current State is state of the bank determined by BS. All entries assume that CKE was active (HIGH) during the preceding clock cycle.
2. Illegal to bank in specified state; Function may be legal in the bank indicated by BS, depending on the state of that bank.
3. Must satisfy bus contention, bus turn around, and/or write recovery requirements.
4. NOP to bank precharging or in Idle state. May precharge bank(s) indicated by BS (andAP).
5. Illegal if any bank is not Idle.
6. CKE Low to High transition will re-enable CLK and other inputs asynchronously. A minimum setup time must be satisfied before any command other than EXIT.
7. Power-Down and Self-Refresh can be entered only from the All Banks Idle State.
8. Must be legal command as defined in the SDRAM function truth table.

Package Diagram 54 PINS TSOP II



① Does not include plastic or metal protrusion of 0.15 max. per side

Unit in inches [mm]

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